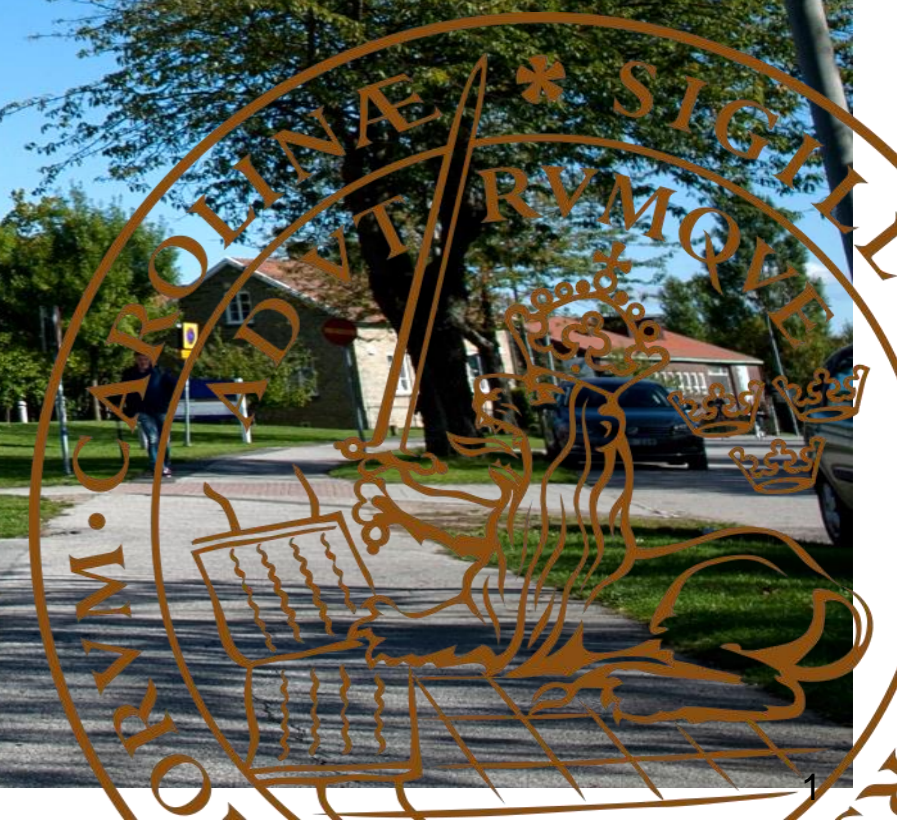


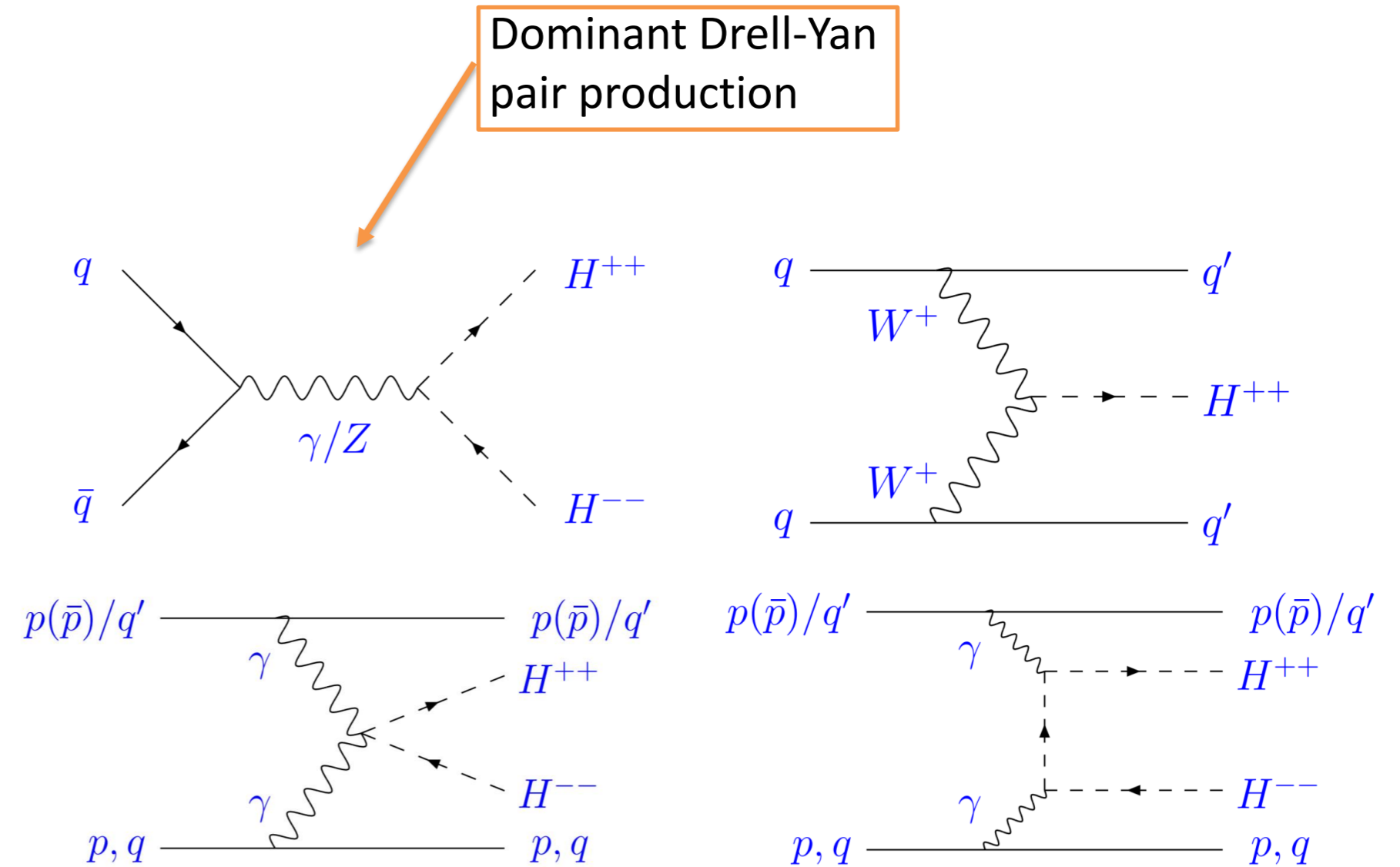
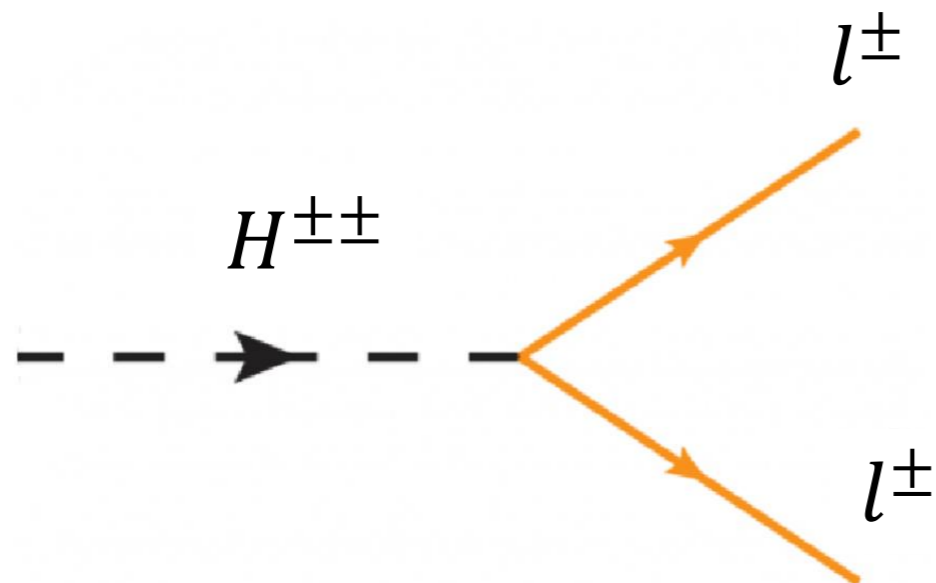
# Search for doubly charged Higgs using Tau leptons with ATLAS at $\sqrt{s} = 13 \text{ TeV}$

Shi Qiu  
Supervisor: Else Lytken  
MPI, 2019



# Why search for doubly charged Higgs?

- Standard Model Higgs Boson is a spinless neutral particle with a vacuum expectation value  $v_0$
- Neutrino oscillation  $\rightarrow$  Neutrino must have mass  $\rightarrow$  **Origin??**
- Doubly charged Higgs bosons can be introduced to explain the origin of neutrino mass!
- Can decay to a pair of same-sign leptons
  - violation of lepton flavour by two units

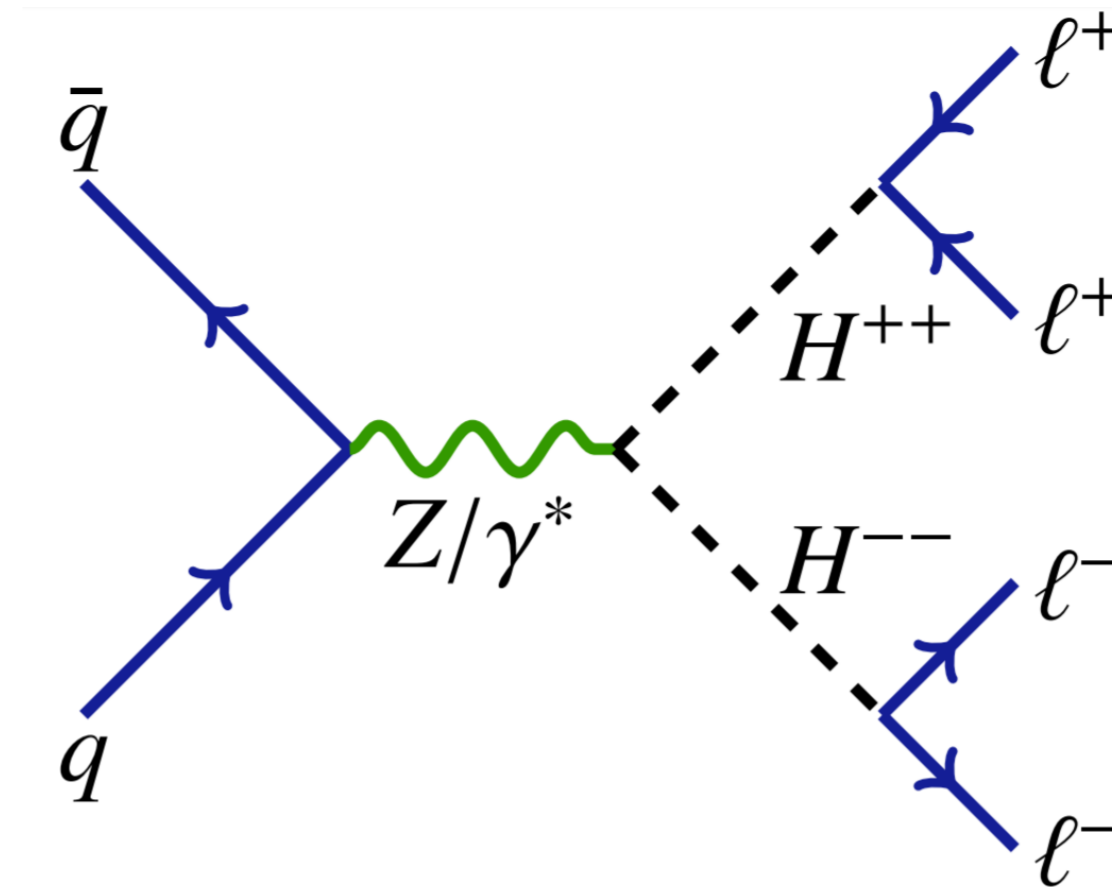


Feynman diagrams for several doubly charged Higgs production channel. arXiv:1105.1379v1



# Previous study by ATLAS on $H^{\pm\pm} \rightarrow l^{\pm}l'^{\pm}$

- Used pp data sample with Integrated luminosity  $36.1 \text{ fb}^{-1}$  collected in 2015 and 2016 by the ATLAS detector at the LHC at  $\sqrt{s}=13 \text{ TeV}$ .
- Only pair production via the Drell–Yan process was considered.
- Masses studied:  $200 \leq m_{H^{\pm\pm}} \leq 1300 \text{ GeV}$
- Only  $e$  and  $\mu$  were considered.
- No significant excess was observed, but lower mass limits were presented (450 GeV for  $B(H^{\pm\pm} \rightarrow l^{\pm}l'^{\pm}) = 10\%$ ).
- Only thing that has not been done is **hadronic decay of  $\tau$**  (leptonic decay of  $\tau$  is reconstructed as  $e$  or  $\mu$ ).



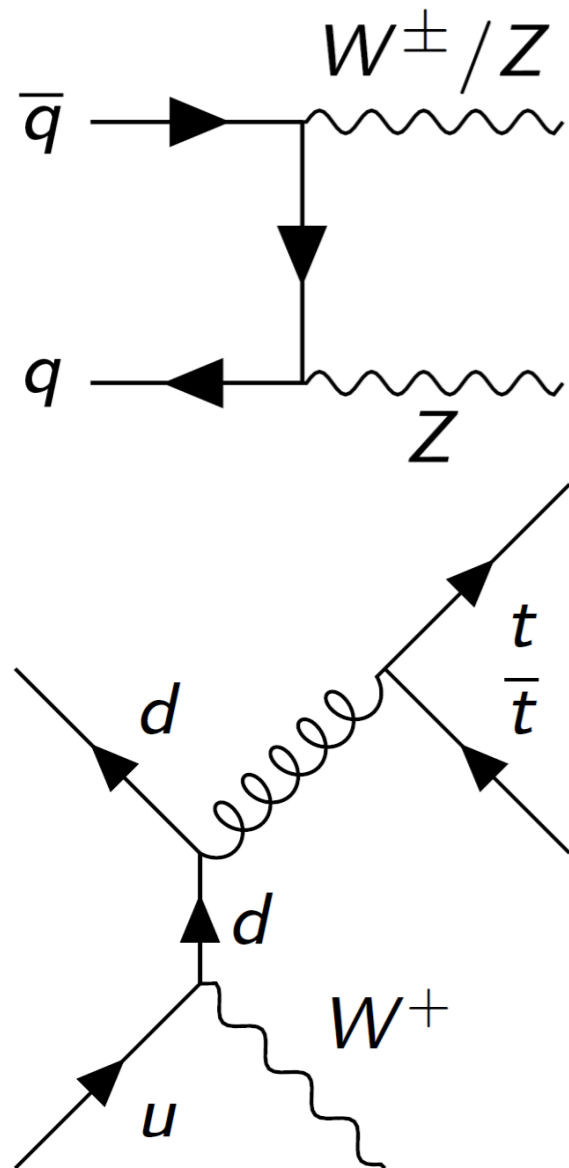
Drell-Yan pair production



# Backgrounds of same-charge hadronic tau

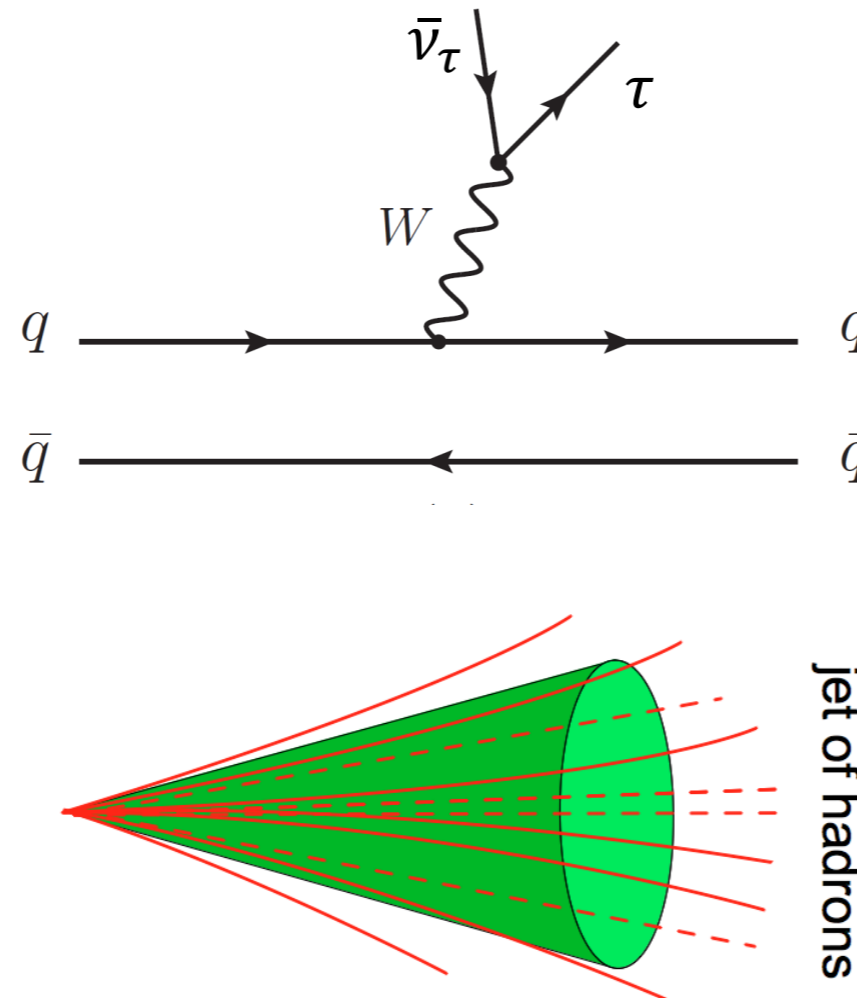
## Prompt

Same-charge taus from SM processes: diboson ( $W^\pm W^\pm / ZZ / WZ$ ) and  $t\bar{t} X$  processes ( $t\bar{t} W$ ,  $t\bar{t} Z$ , and  $t\bar{t} H$ )



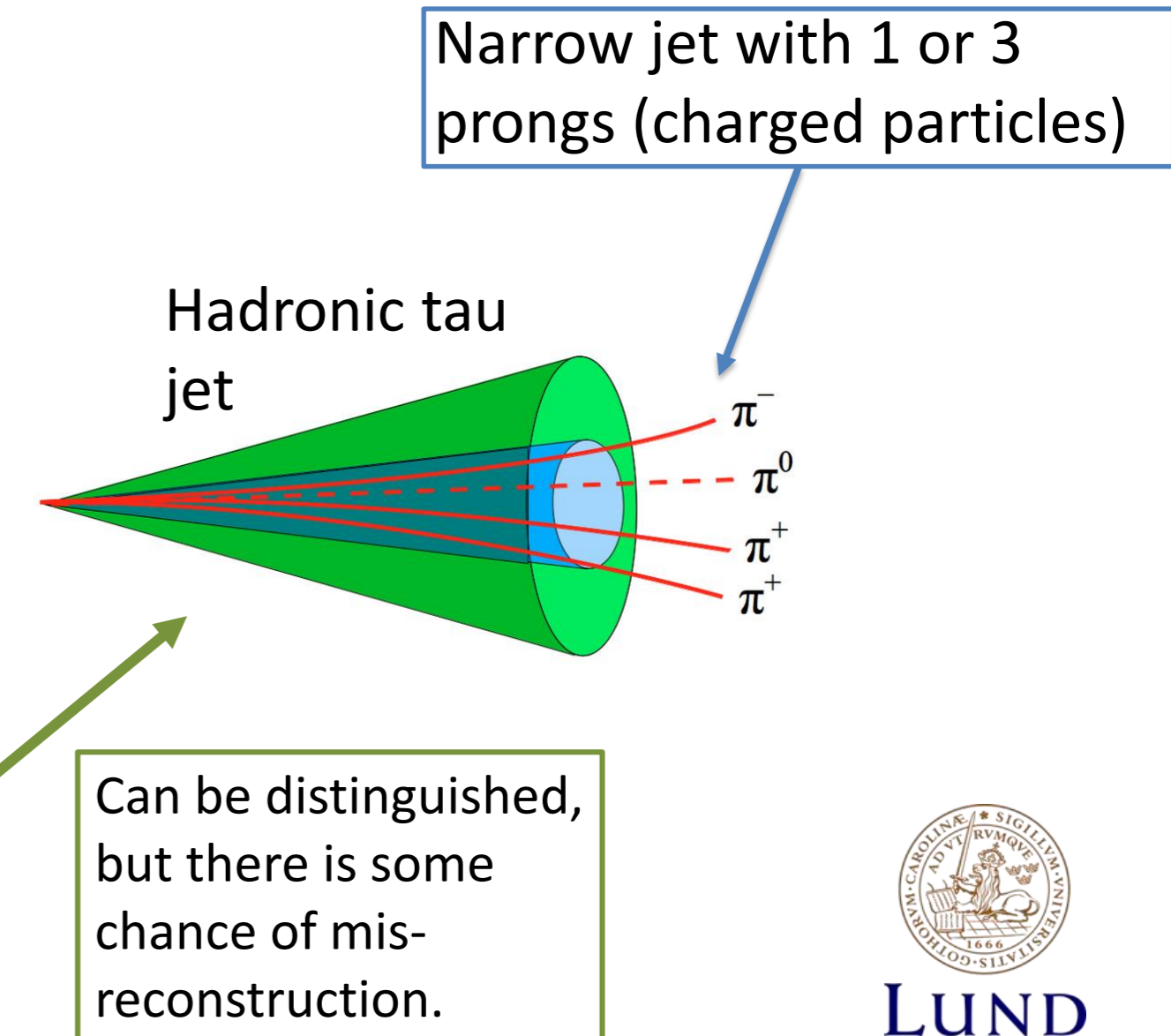
## Non-prompt

Real taus from non-prompt decays, e.g. from heavy flavored mesons  
Jets mis-reconstructed as taus



## Charge-flip

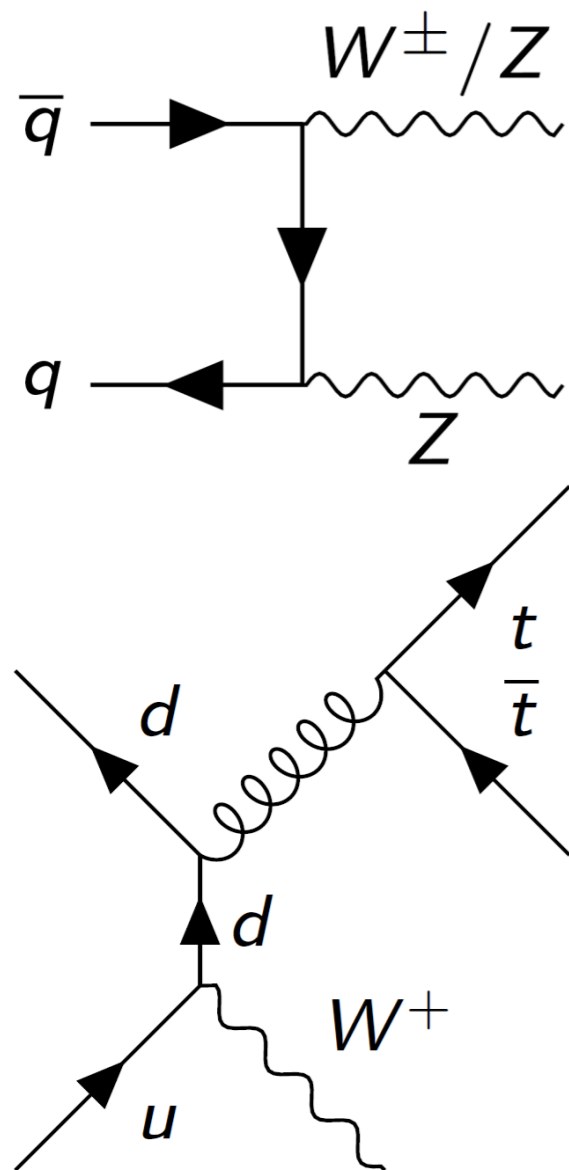
Oppositely charged leptons with charge of tau misidentified:  
 $Z/\gamma^*$ ,  $t\bar{t}$ ,  $tW$ ,  $W^\pm W^\mp$



# Backgrounds

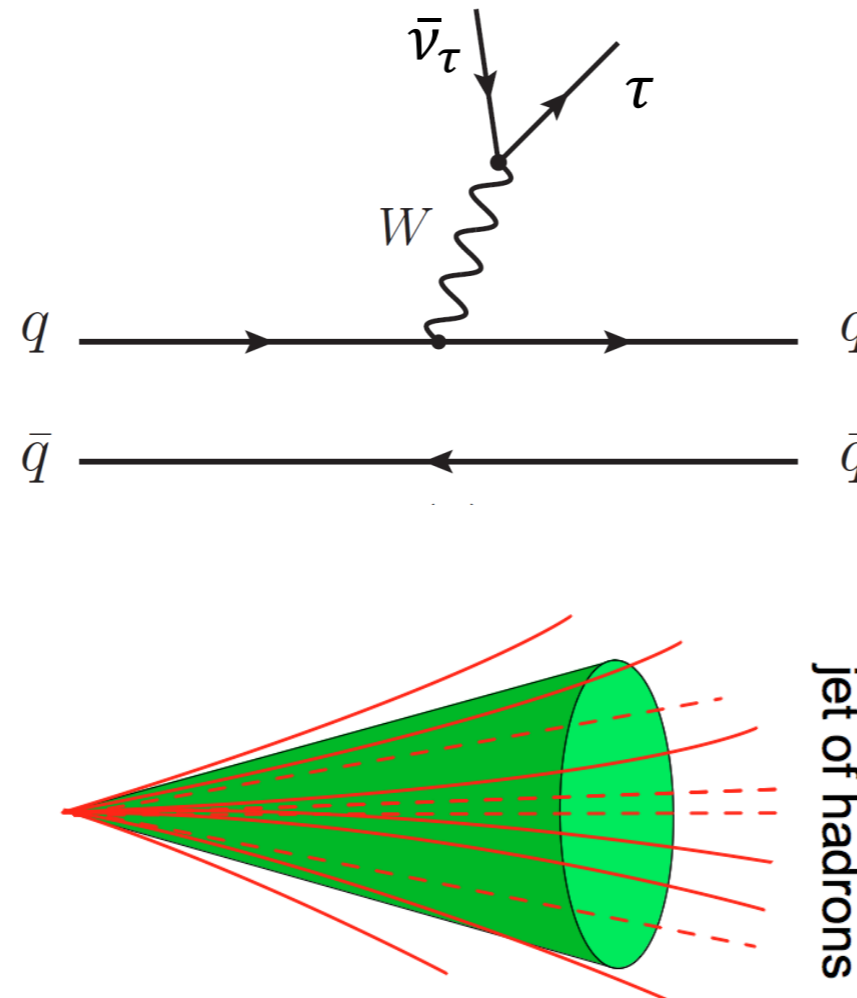
## Prompt

Same-charge taus from SM processes: diboson ( $W^\pm W^\pm / ZZ / WZ$ ) and  $t\bar{t} X$  processes ( $t\bar{t} W$ ,  $t\bar{t} Z$ , and  $t\bar{t} H$ )



## Non-prompt

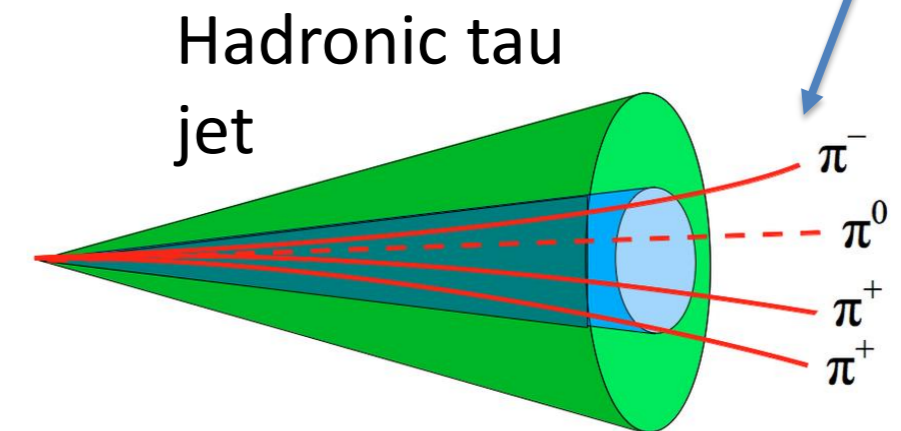
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## Charge-flip

Oppositely charged leptons with charge of tau misidentified:  
 $Z/\gamma^*$ ,  $t\bar{t}$ ,  $tW$ ,  $W^\pm W^\mp$

Narrow jet with 1 or 3 prongs (charged particles)



What I work on!

# Hadronic tau charge-flip background studies

- Using three methods to perform charge-flip rate study of tau for MC and data.
- What we want at the end?
  - **scale factor**: ratio of the charge-flip rate between MC and data
  - apply the scale factor to the simulated events to compensate for the differences
- **Data-drive** and **tag-and-probe** method
  - used in previous charge-flip study on electron for MC and data.
  - not working for tau data due to heavily contaminated background
- **Template fit** method
  - a new method designed for studying the hadronic tau charge-flip rate of data

Type	Method	Samples	Channel
MC	Data-driven	Ztautau ttbar	Ditau ( $\tau_{had}\tau_{had}$ )
	Tag-and-probe	Ztautau ttbar	muTau ( $\tau_{\mu}\tau_{had}$ )
Data	Template fit	2015-2017	muTau ( $\tau_{\mu}\tau_{had}$ )

# Data-driven method

- Assume **Poissonian distribution** for expected number of charge flipped events  $\lambda$

$$P(N_{SS}; \lambda) = \frac{\lambda^{N_{SS}} e^{-\lambda}}{N_{SS}!}$$

where  $\lambda$  is a function of the charge flip probability  $\epsilon(p_T, \eta) = f(\eta) \cdot \sigma(p_T)$ .

- The expected number of charge flipped events:

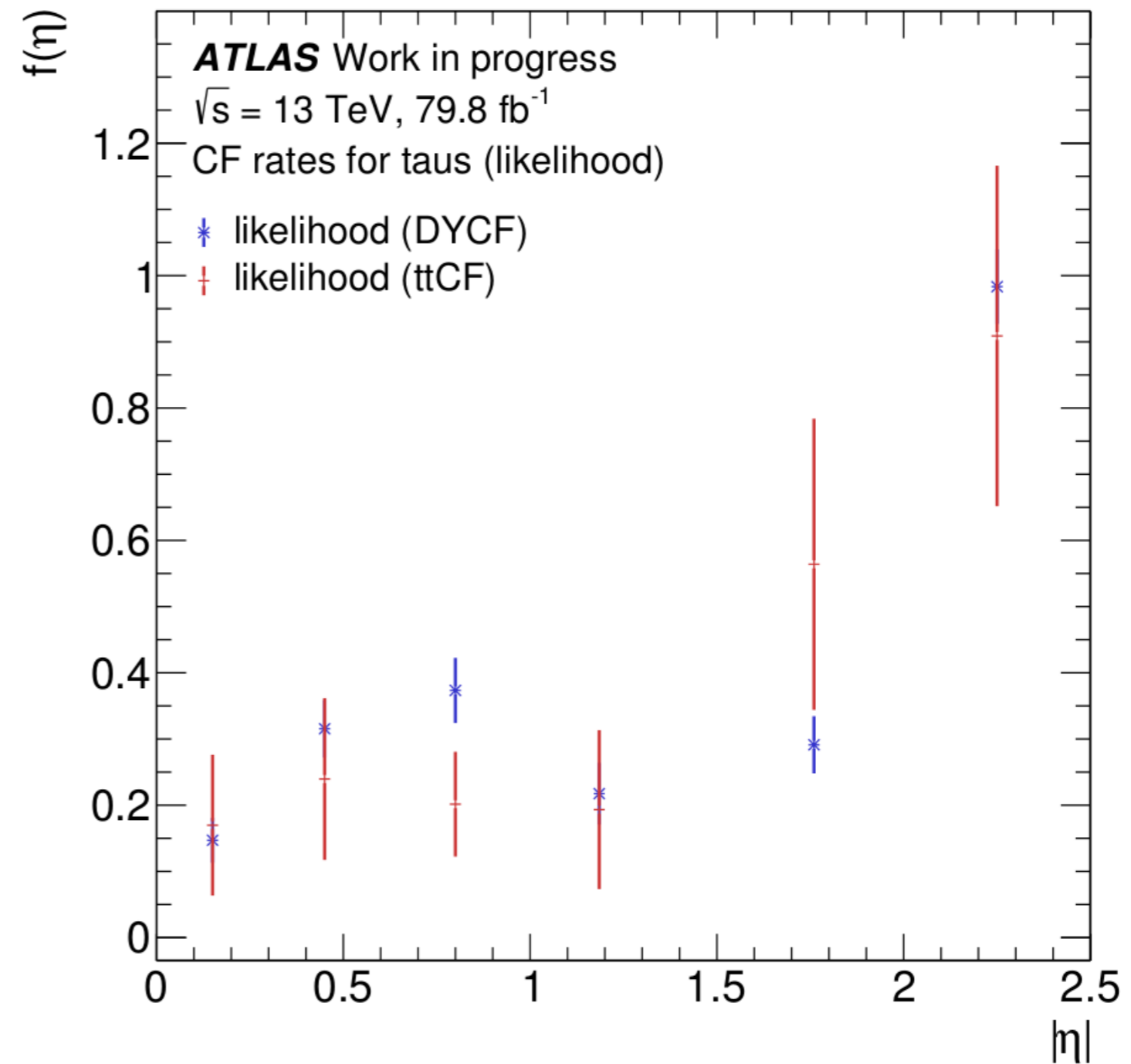
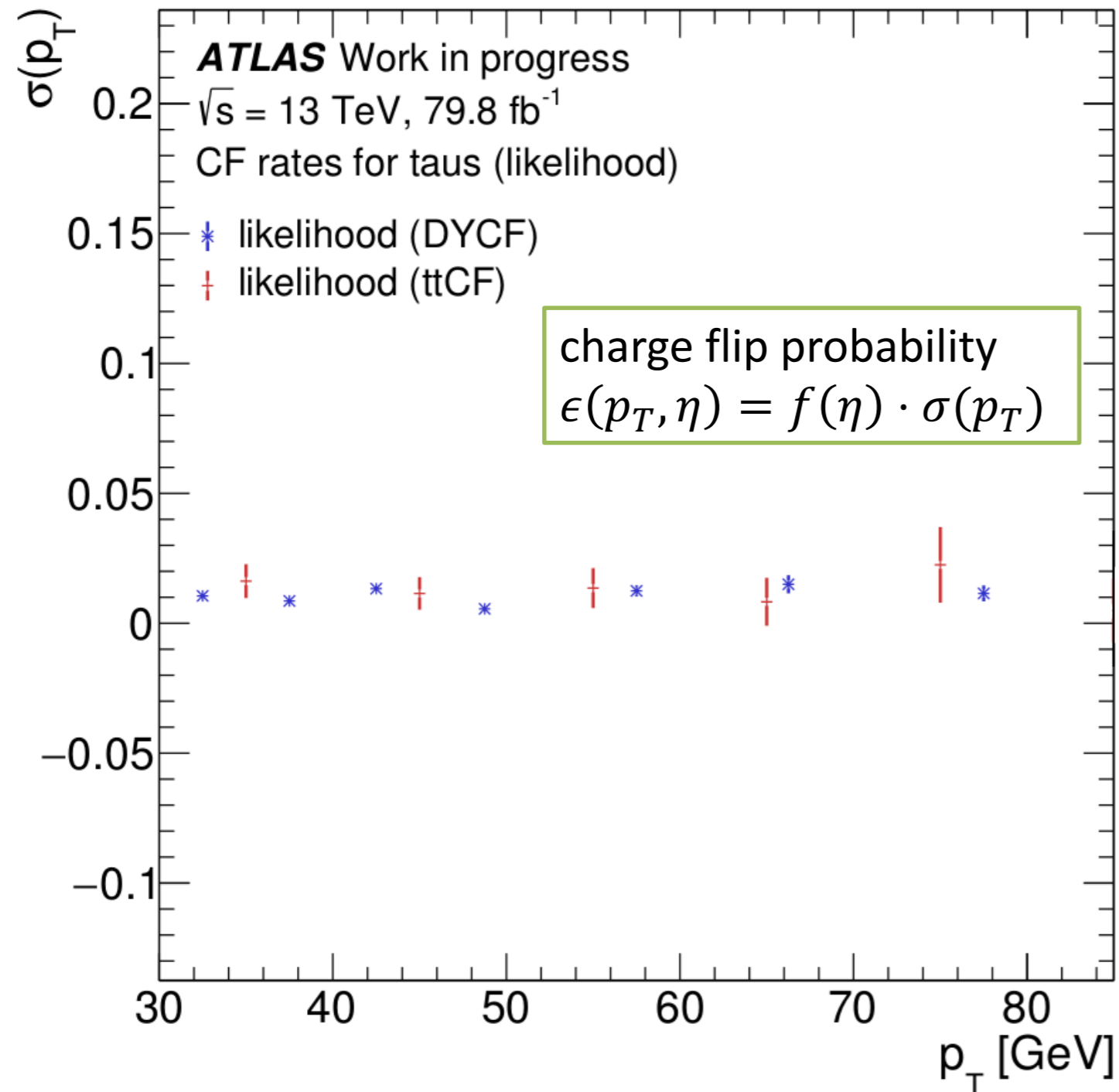
$$\lambda_{i,j} = \epsilon_i (1 - \epsilon_j) N_{AS}^{ij} + (1 - \epsilon_i) \epsilon_j N_{AS}^{ij}$$



	Selections
Baseline	Di-tau trigger
	Two taus (BDT medium working point). Electron and muon veto
	Tau $p_T > 30$ GeV, truth matched
ttbar sample	At least one b-jet
Ztautau sample	No extra cuts for MC samples



# Charge-flip rate for MC estimated by data-driven method





# Tag-and-probe method

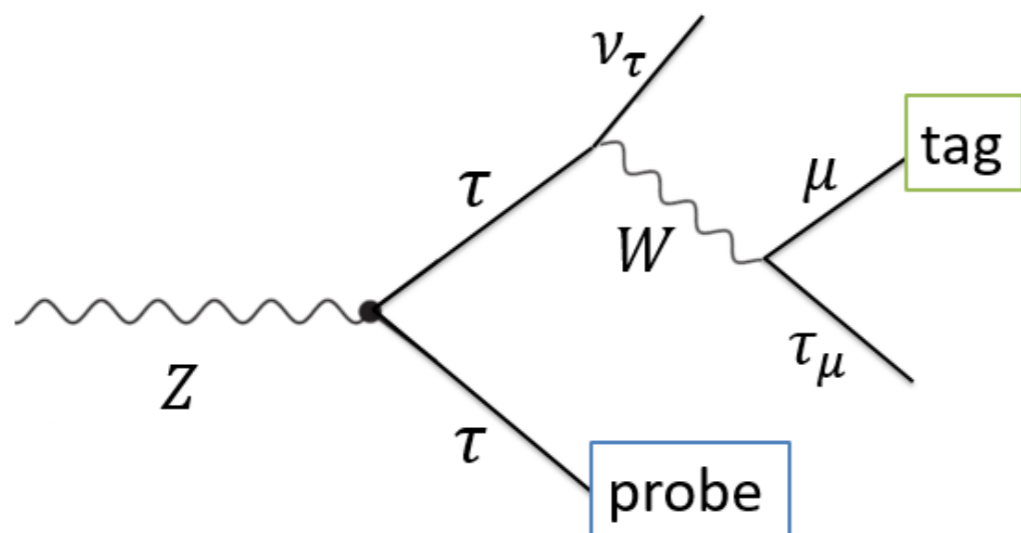
- Estimate the charge flip rate using following decay

$$Z/t\bar{t} \rightarrow \tau\tau \rightarrow \tau_{had}\tau_{\mu}$$

- Muon charge (the tag) is assumed to be reliably reconstructed to estimate the charge flip rate of tau (the probe)

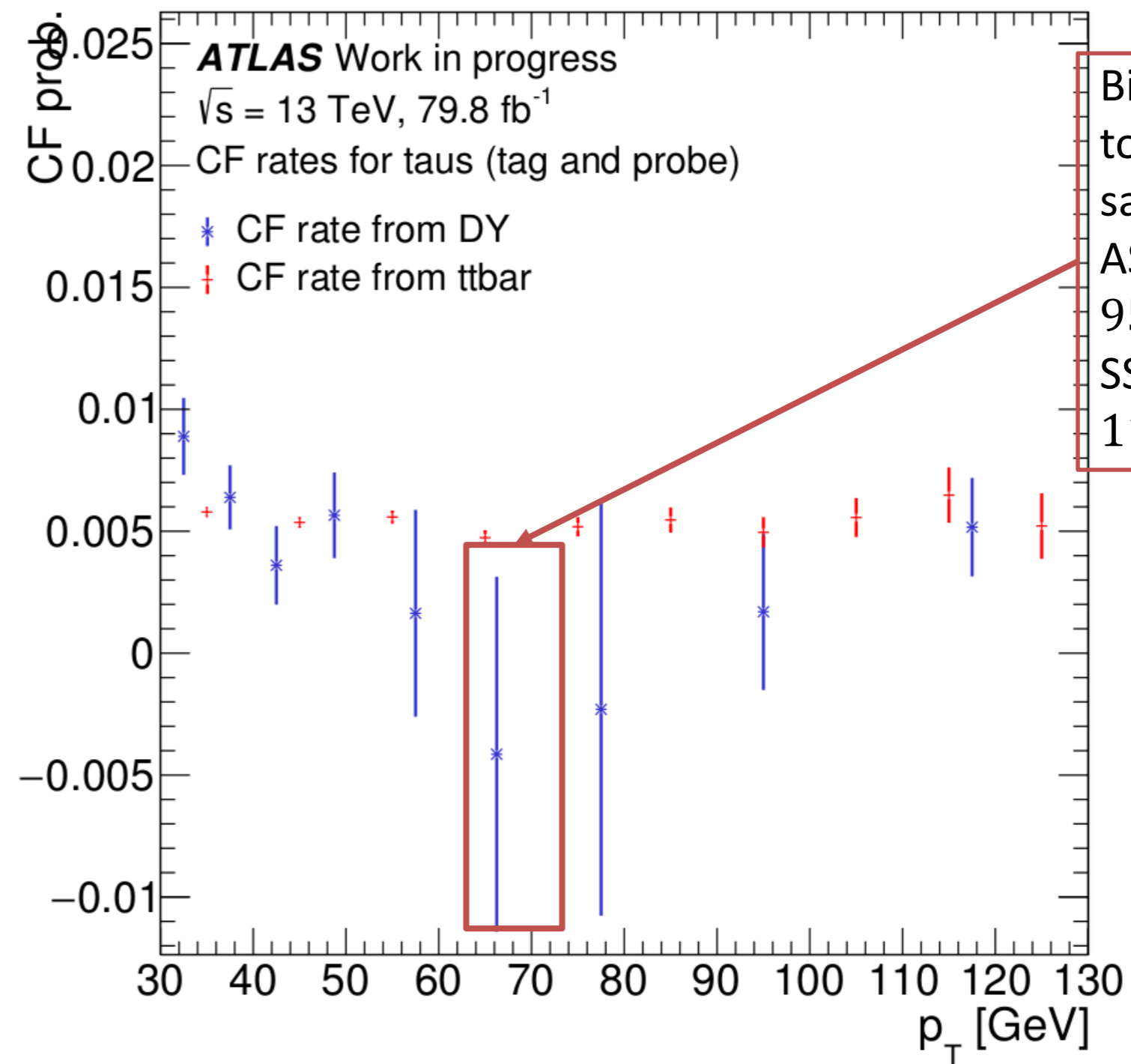
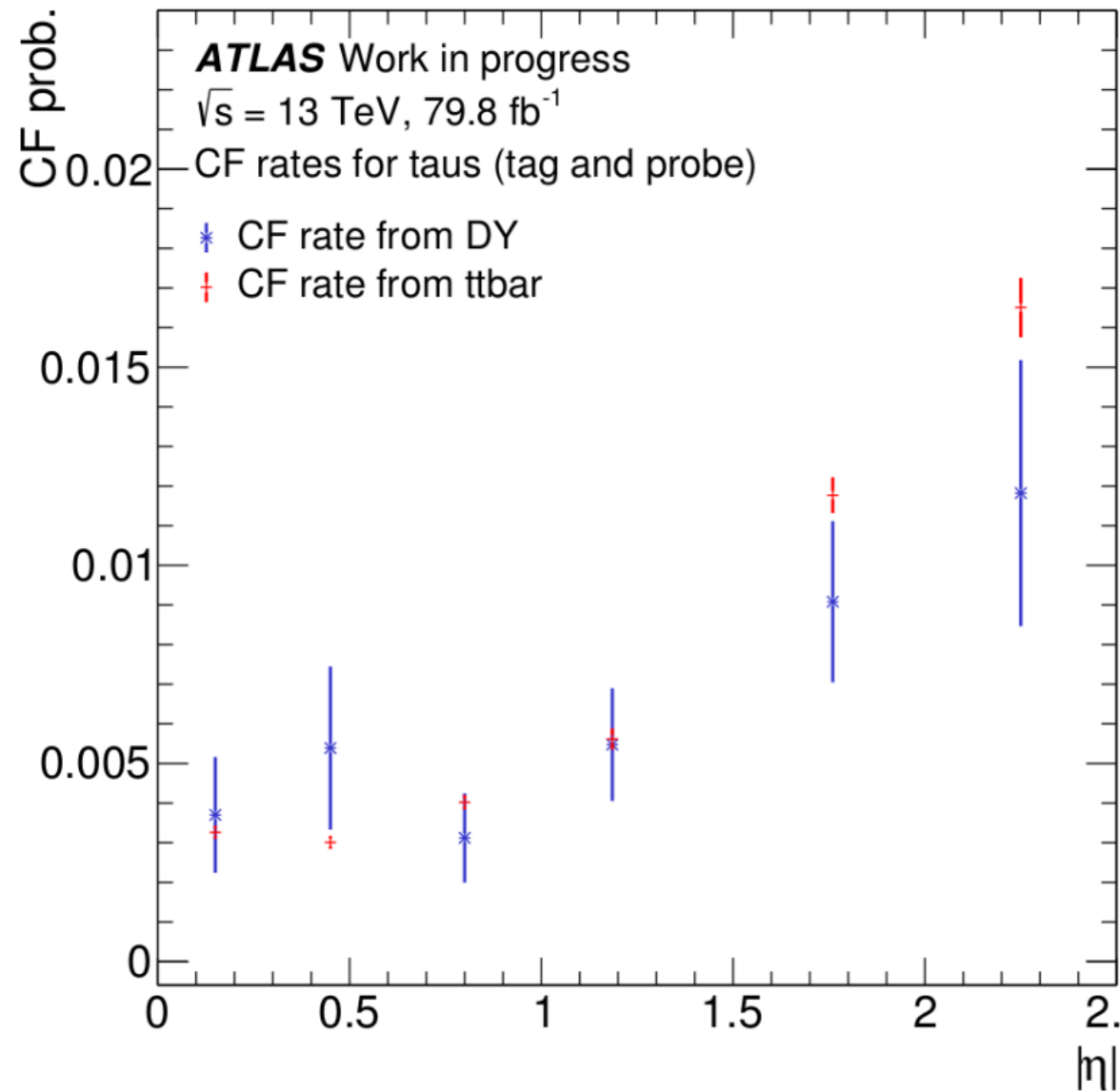
$$\epsilon_{\tau_{had}} = \frac{N_{SS}}{N_{AS}}$$

- $\epsilon_{\tau_{had}}$  depends only on  $p_T$  **or**  $\eta$  due to consideration of statistics



	Selections
Baseline	Single muon trigger:
	One muon and one tau (BDT medium working point). Electron veto
	Muon: $p_T > 30$ GeV, $z_0 \sin \theta < 0.5$ , $d_0 \text{sig} < 3.0$ Tau: $p_T > 30$ GeV, truth matched
ttbar sample	At least one b-jet
Ztautau	No extra cuts for MC samples

# Charge-flip rate from tag-and-probe method

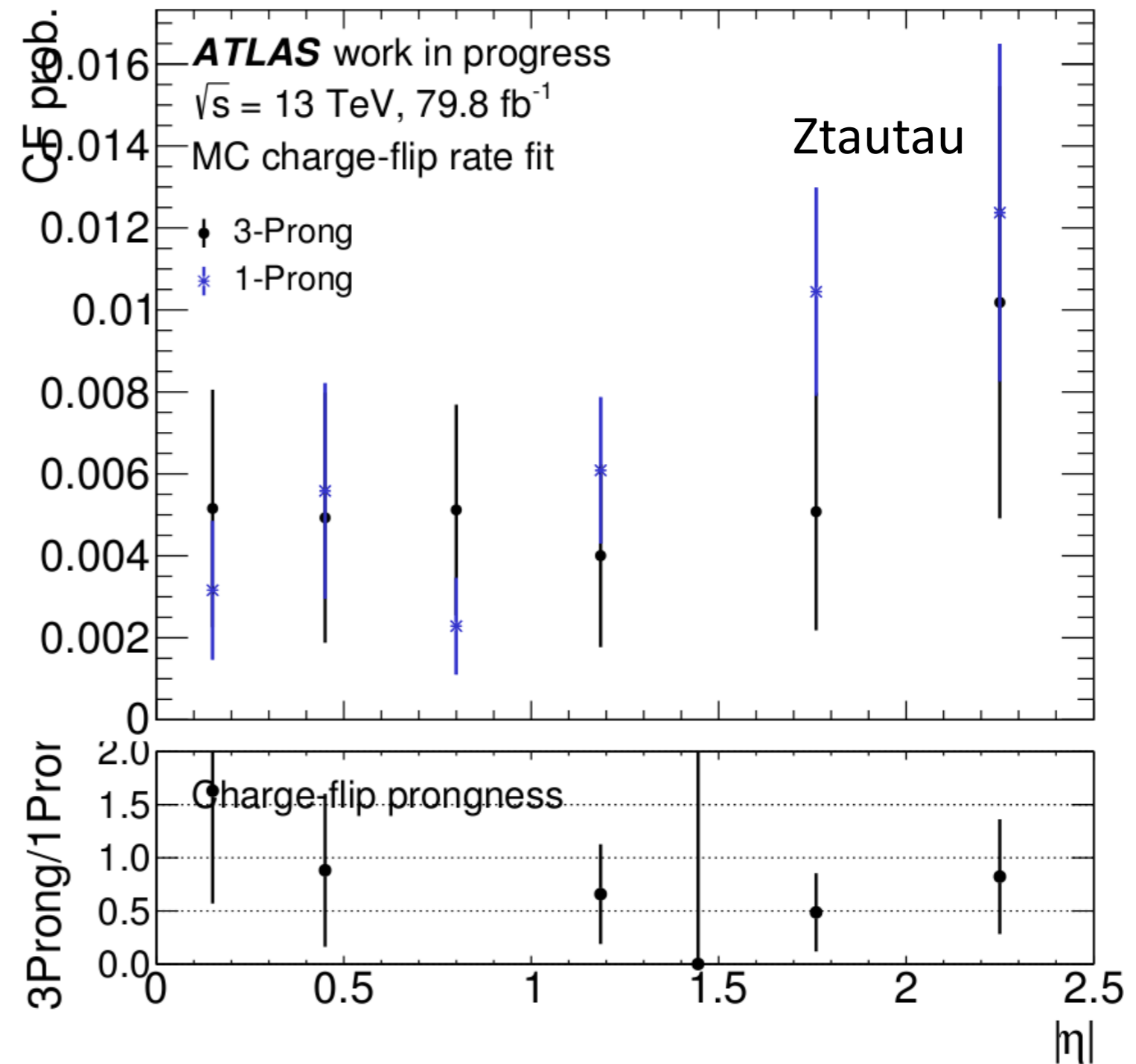
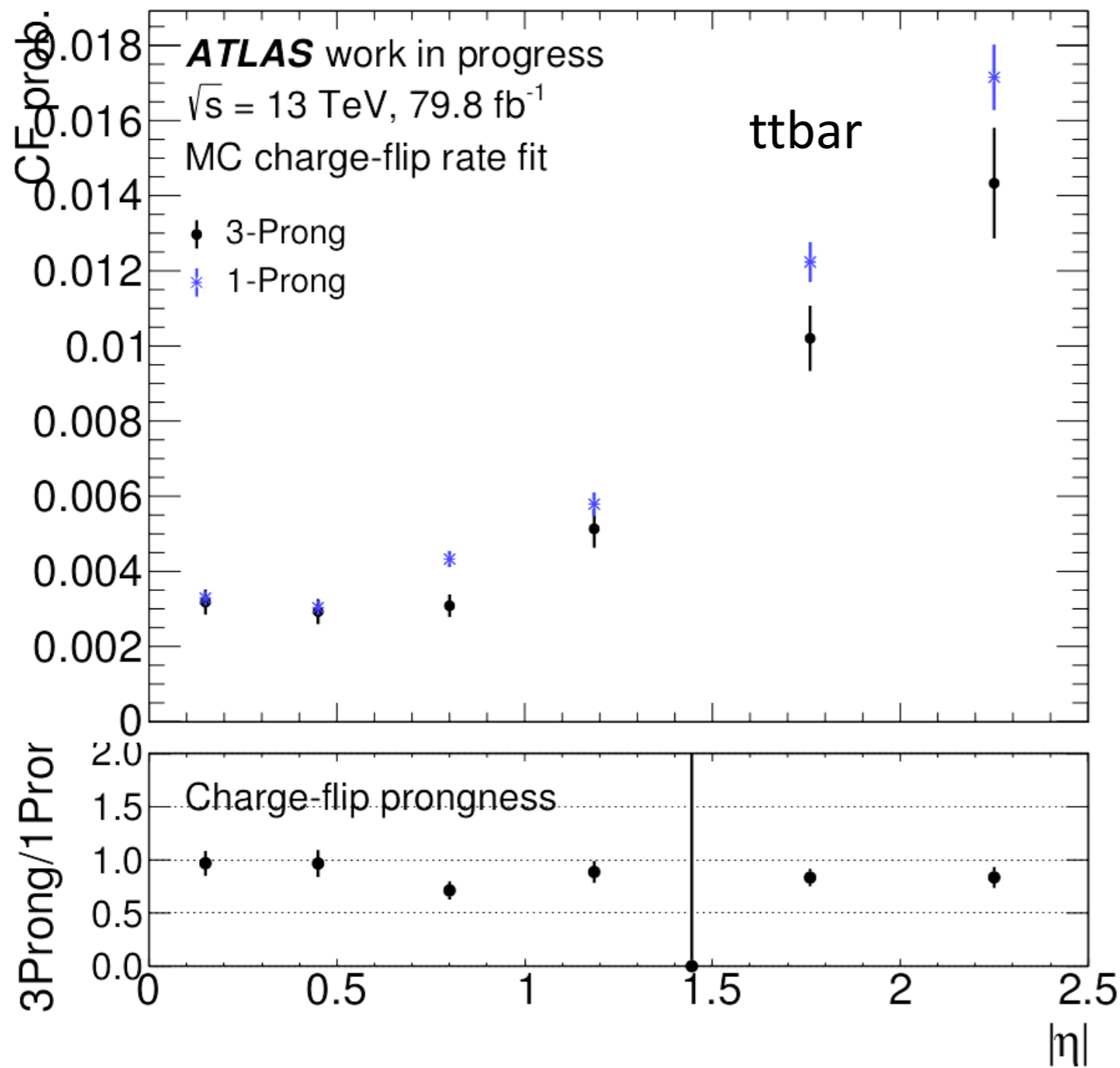


Big error bar due to large error in same sign fill:  
 $AS_{pt} = 1538 \pm 95$   
 $SS_{pt} = -6.37 \pm 11.19$

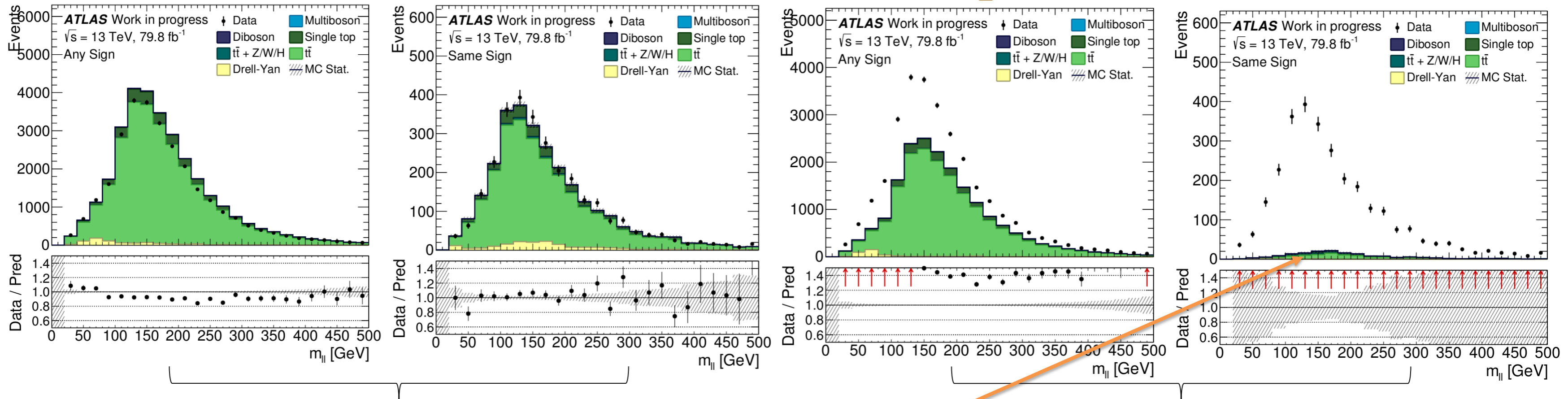
Weak dependence on  $p_T$



# Comparison of charge-flip rate $\epsilon_{\tau_{had}}(\eta)$ between 1-prong and 3-prong



# Difficulties in studying hadronic tau charge-flip rate for data illustrated using $t\bar{t}$ control region



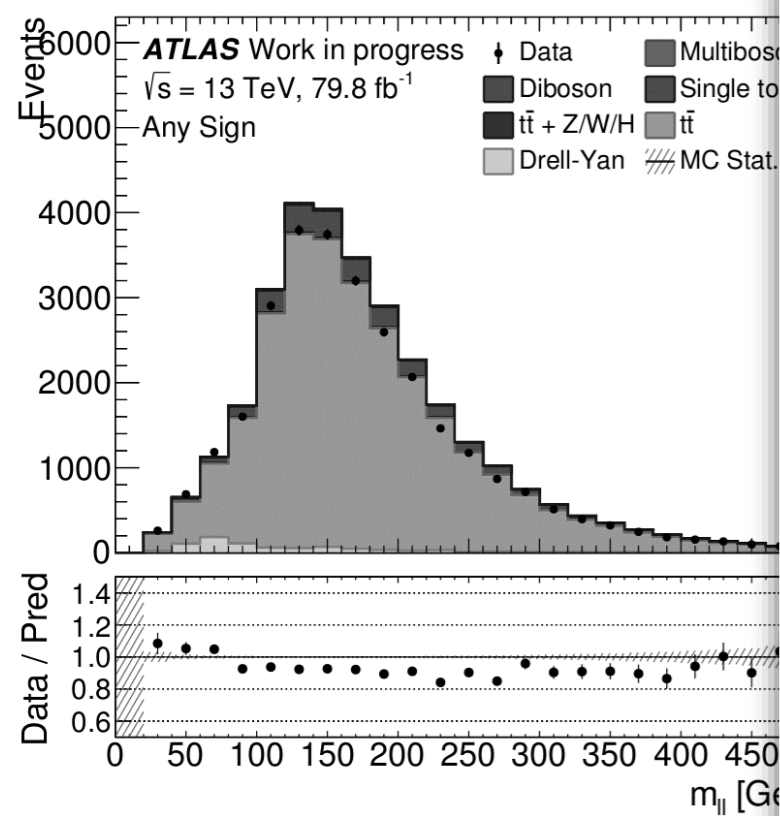
Inclusive: no truth matching of taus and muons

Truth matched: taus and muons are matched to their origin

MC plot shows that the number of true SS muon tau events is very small. The SS data are **heavily contaminated by fake taus**

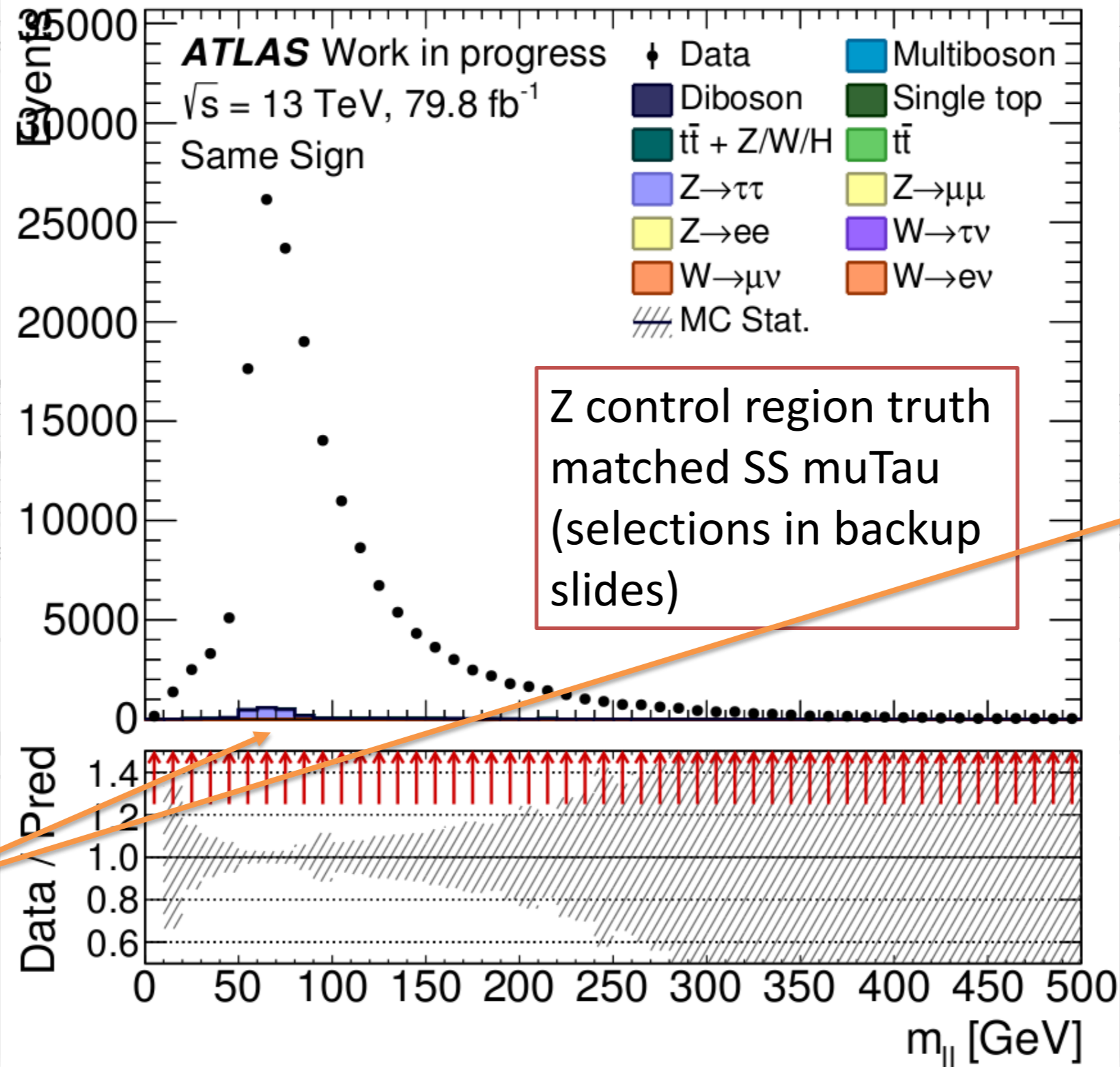


# Ztautau control region has worse statistics

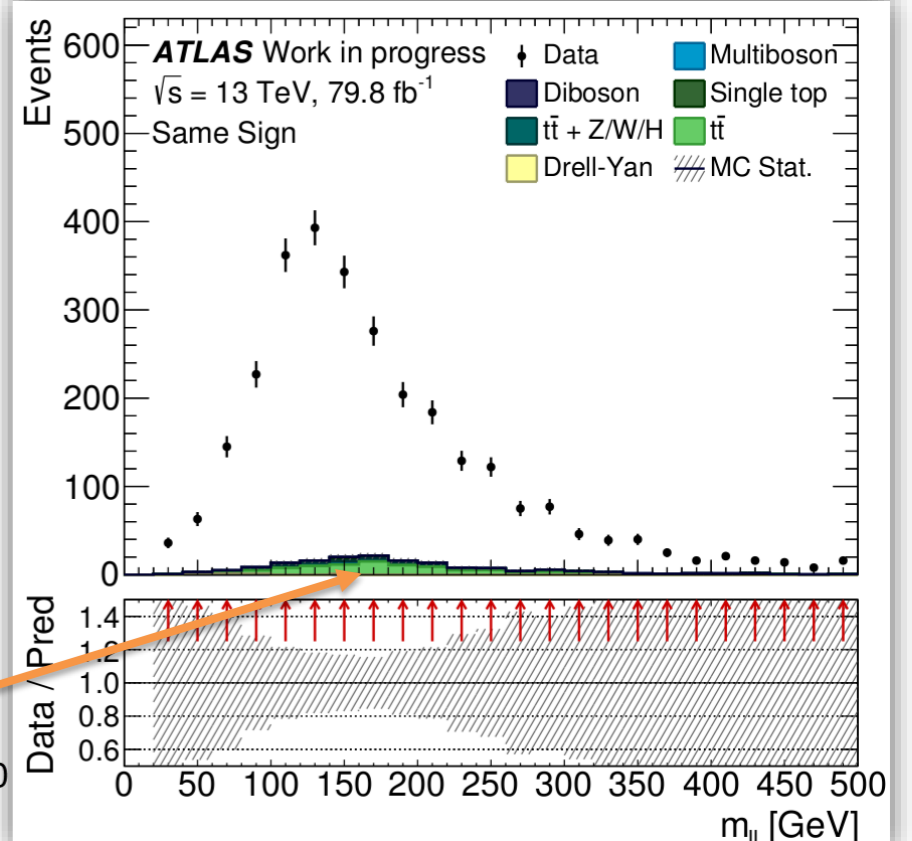
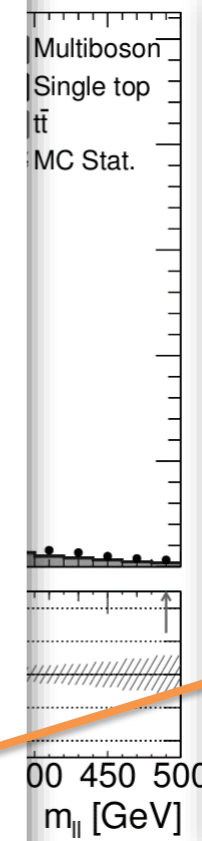


Inclusive: n of tau and

More events in  $t\bar{t}$  in comparing to Z control region



Z control region truth matched SS muTau (selections in backup slides)



matched: taus and s are matched to their



# Template fit method

- Choose to use **ttbar sample** and **muTau** ( $\tau_\mu\tau_{had}$ ) channel to build the templates due the highest statistics it has
- $\epsilon_{\tau_{had}}$  **depends only on  $\eta$**
- Using muTau channel means that tau is always assumed to be the one with wrong charge, just like the tag-and-probe
- The compositions of AS and SS raw data can be separate to two parts

$$N_{data}^{AS}(\eta_i) = N_{signal}^{AS}(\eta_i) + N_{bck}^{AS}(\eta_i)$$

$$N_{data}^{SS}(\eta_i) = N_{signal}^{SS}(\eta_i) + N_{bck}^{SS}(\eta_i)$$

	Selections
Baseline	Single muon trigger
	One muon and one tau (BDT medium working point). Electron veto
	Muon: $p_T > 30$ GeV, $z_0\sin\theta < 0.5$ , $d_0\text{sig} < 3.0$ Tau: $p_T > 30$ GeV, medium wp, isoTau, hadronic tau
ttbar control region	Tau: $p_T > 50$ GeV, muon: $p_T > 50$ GeV
	At least one b-jet



# Template fit method

- Four templates are required:

- $TMPL(N_{signal}^{AS})$  comes from  $N_{truth MC}^{AS}$
- $TMPL(N_{bck}^{AS})$  comes from  $N_{inc. MC}^{AS} - N_{truth MC}^{AS}$
- $TMPL(N_{signal}^{SS})$  comes from  $N_{truth MC}^{SS}$
- $TMPL(N_{bck}^{SS})$  comes from  $N_{inc. MC}^{SS} - N_{truth MC}^{SS}$

- Need to find optimum values for the parameter  $a, b, c, d$ :

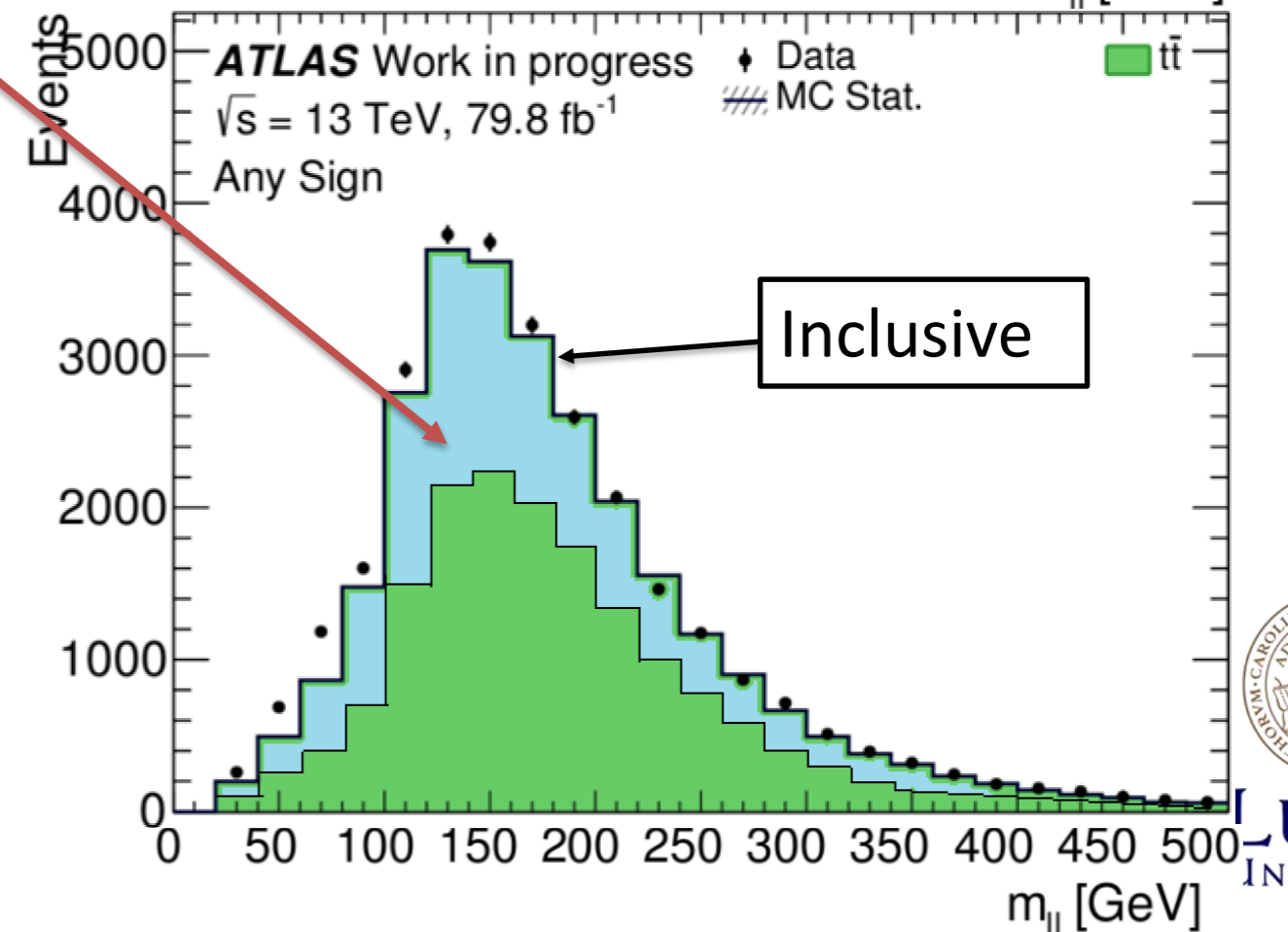
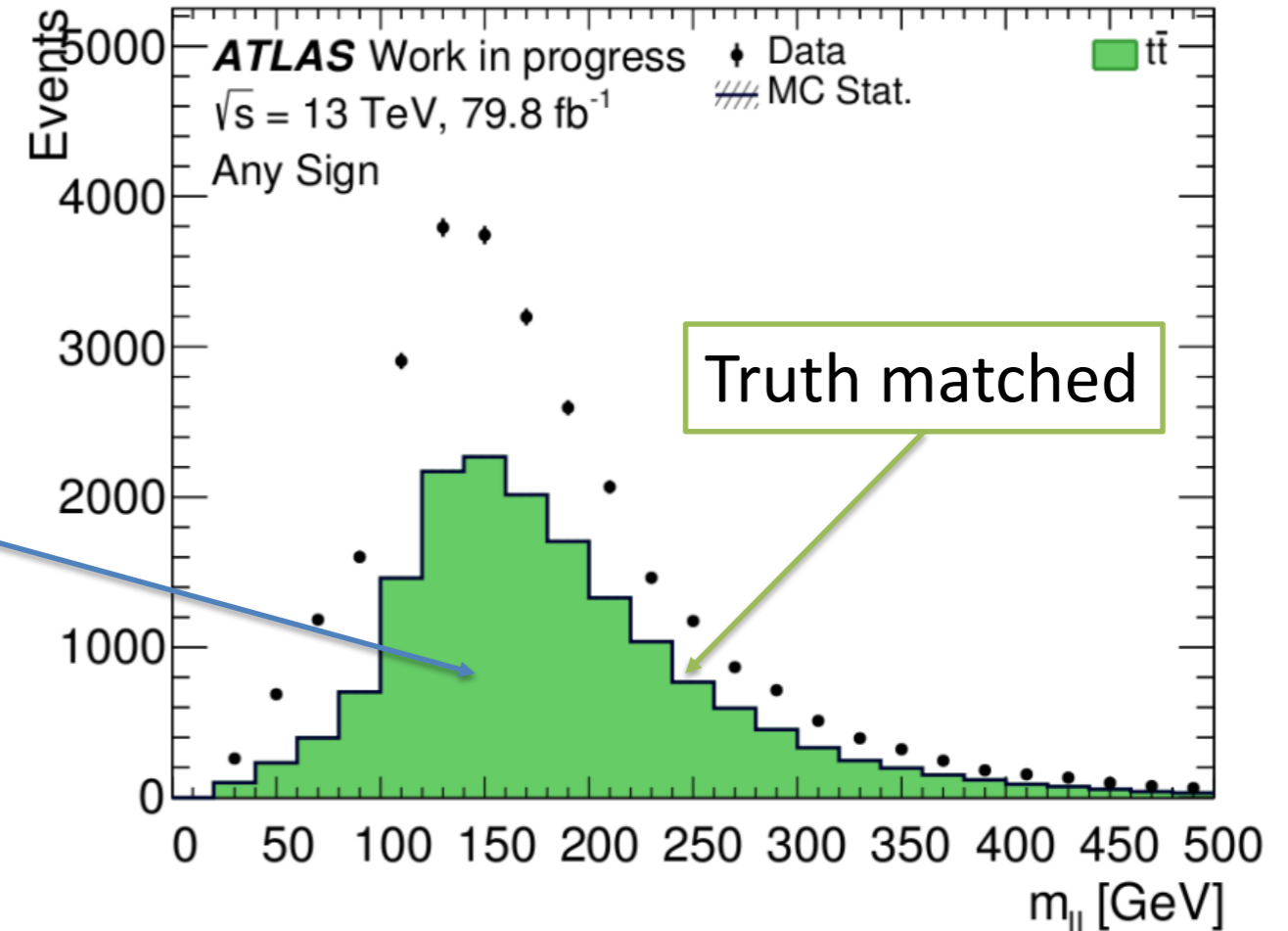
$$N_{data}^{AS}(\eta_i) = a \cdot TMPL(N_{signal}^{AS}(\eta_i)) + b \cdot TMPL(N_{bck}^{AS}(\eta_i))$$

$$N_{data}^{SS}(\eta_i) = c \cdot TMPL(N_{signal}^{SS}(\eta_i)) + d \cdot TMPL(N_{bck}^{SS}(\eta_i))$$

Parameter	$a$	$b$	$c$	$d$
Best fit value	0.820	1.377	1.364	1.223
	$\pm 0.045$	$\pm 0.070$	$\pm 1.862$	$\pm 0.078$

- The charge flip rate is

$$\epsilon_{had}(\eta_i) = \frac{c \cdot TMPL(N_{signal}^{SS}(\eta_i))}{a \cdot TMPL(N_{signal}^{AS}(\eta_i))}$$



# Template fit method

- Four templates are required:
  - $TMPL(N_{signal}^{AS})$  comes from  $N_{truth MC}^{AS}$
  - $TMPL(N_{bck}^{AS})$  comes from  $N_{inc. MC}^{AS} - N_{truth MC}^{AS}$
  - $TMPL(N_{signal}^{SS})$  comes from  $N_{truth MC}^{SS}$
  - $TMPL(N_{bck}^{SS})$  comes from  $N_{inc. MC}^{SS} - N_{truth MC}^{SS}$
- Need to find optimum values for the parameter  $a, b, c, d$ :

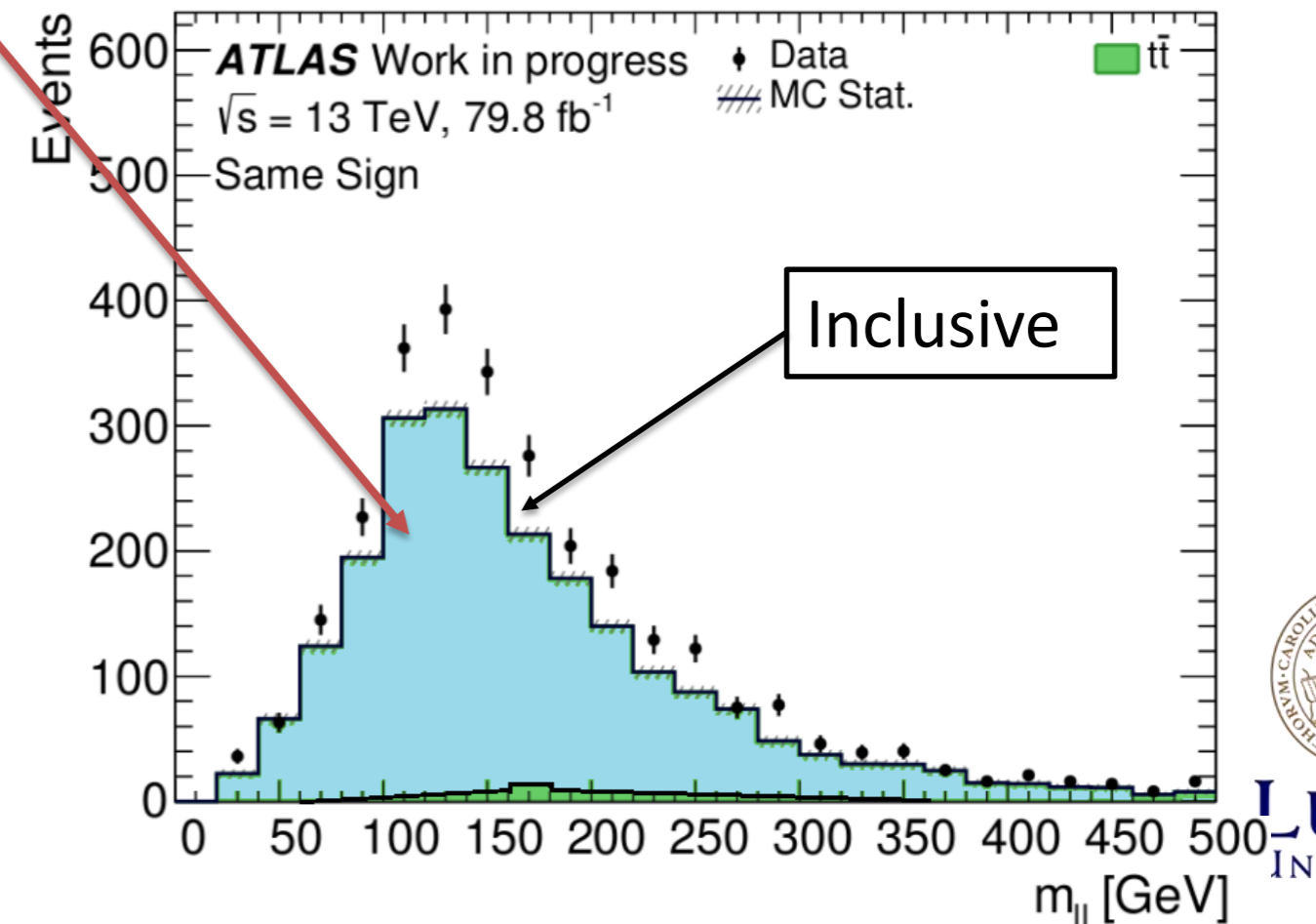
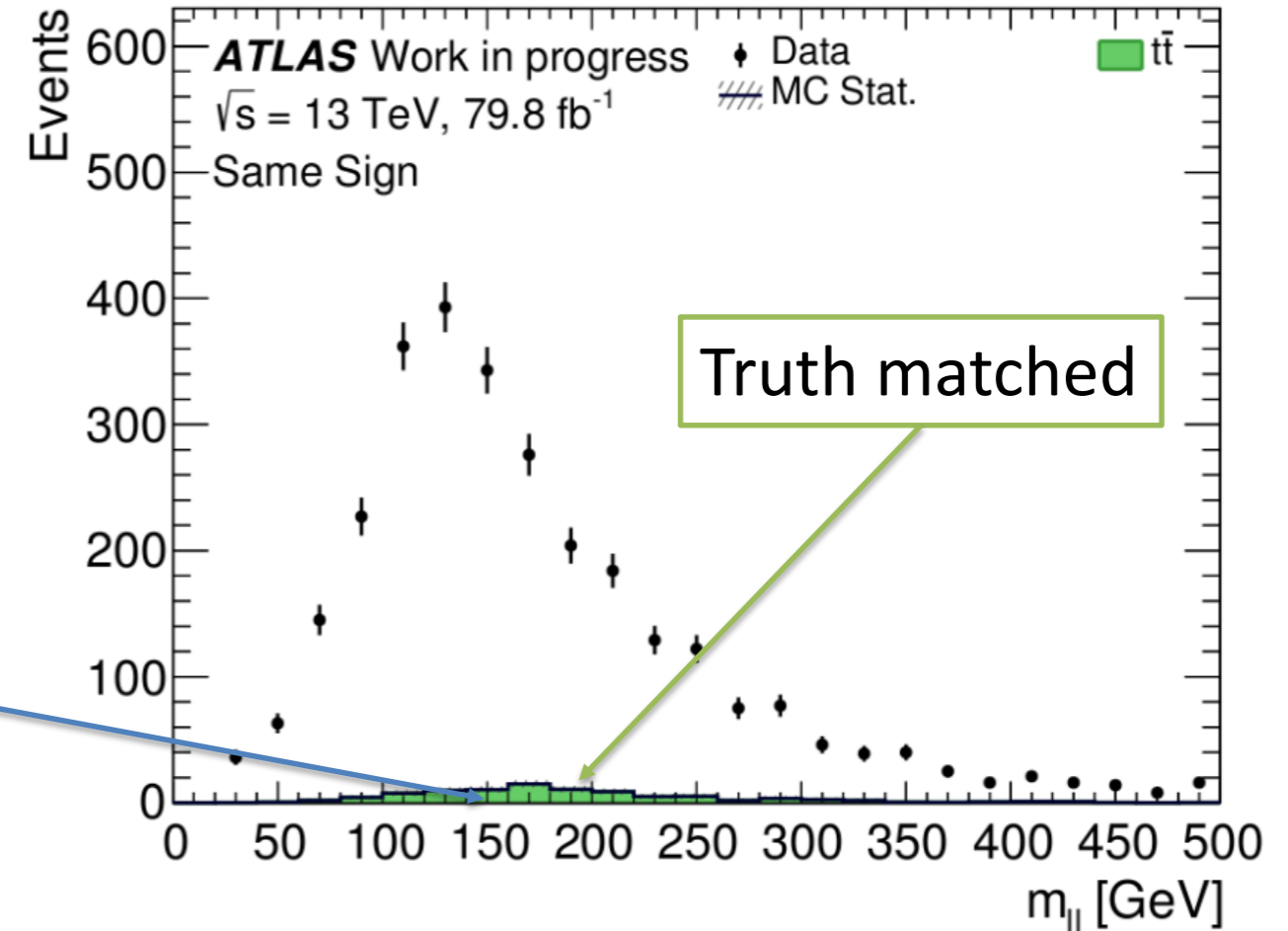
$$N_{data}^{AS}(\eta_i) = a \cdot TMPL(N_{signal}^{AS}(\eta_i)) + b \cdot TMPL(N_{bck}^{AS}(\eta_i))$$

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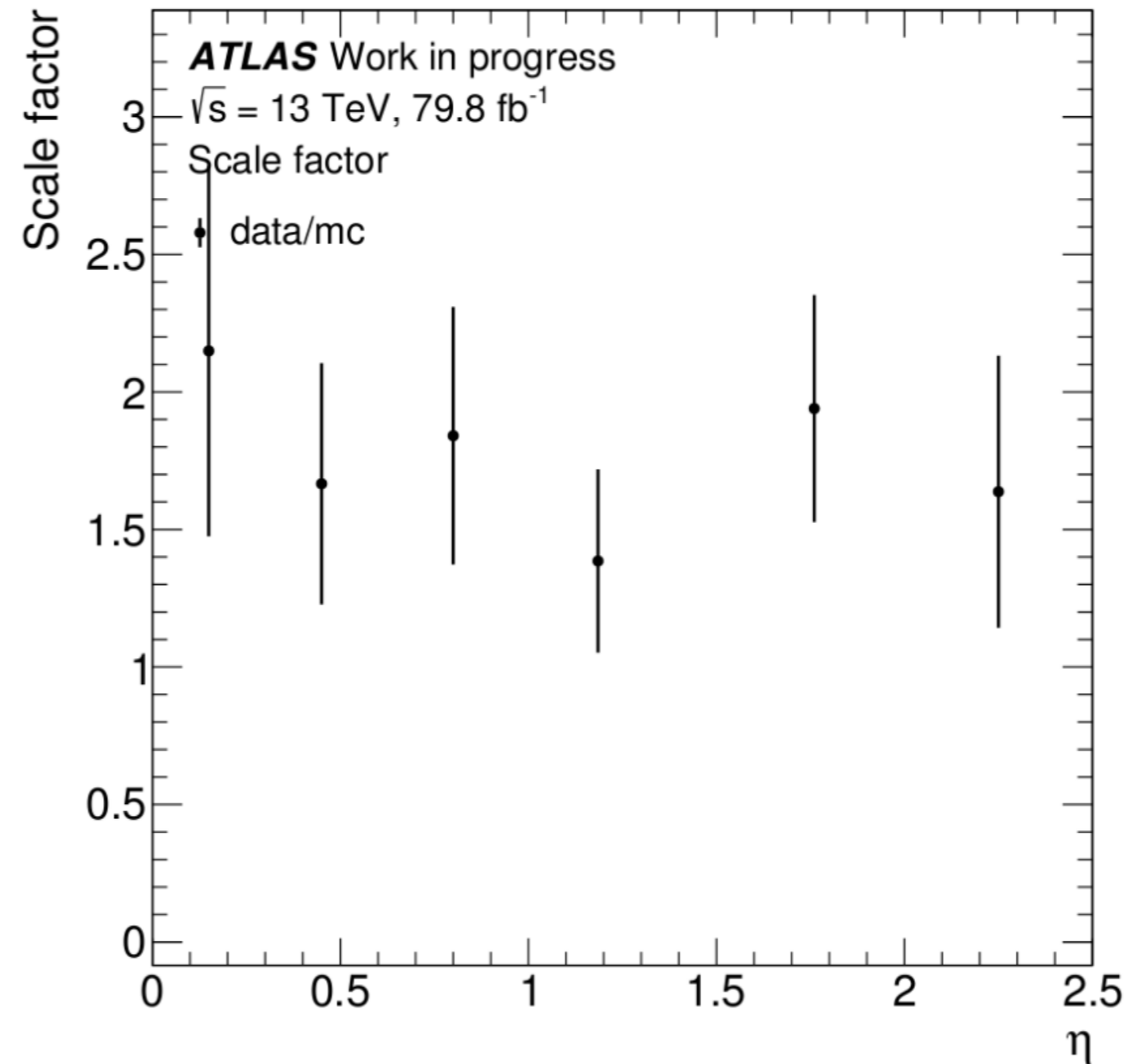
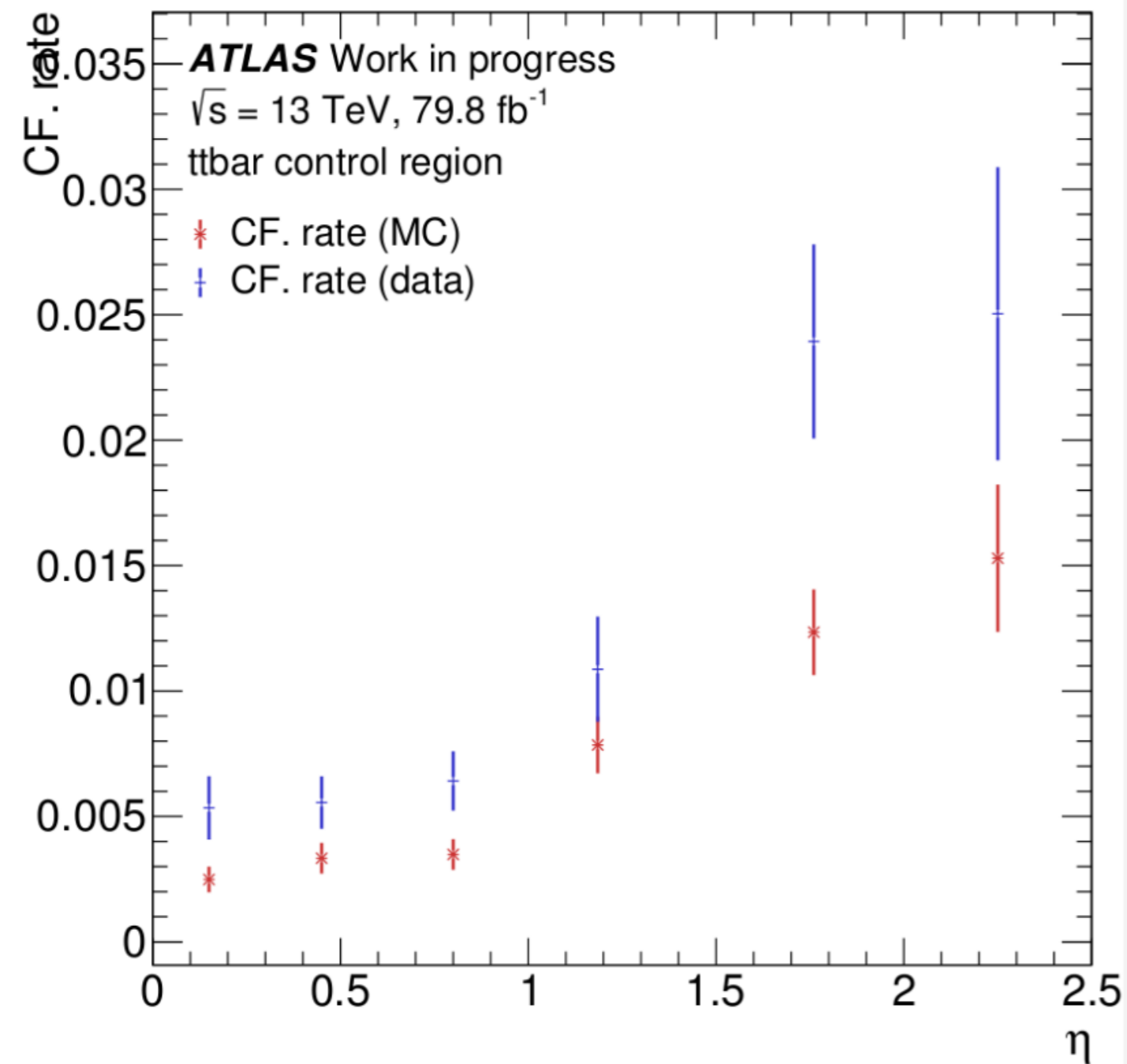
- The charge flip rate is

$$\epsilon_{had}(\eta_i) = \frac{c \cdot TMPL(N_{signal}^{SS}(\eta_i))}{a \cdot TMPL(N_{signal}^{AS}(\eta_i))}$$





# Charge flip rate for data and scale factor



# Conclusion and current status

- The ATLAS detector at LHC is currently used to search for doubly charged Higgs bosons using same-charge hadronic tau channel.
- Charge-flip rate of hadronic tau  $\epsilon_{had}$  for MC and data have been studied.
- $\epsilon_{had}$  depends weakly on  $p_T$  and strongly on  $\eta$ .
- The charge-flip background is not a dominant background. Only 0.5 – 2% for  $|\eta|$  ranging from 0 to 2.5.
- The scale factor is derived to be around  $2 \pm 0.5$ .
- **Currently** study the cause of charge-flip rate using event display



# Backup slides



# Why search for doubly charged Higgs?

- Doubly charged Higgs bosons can arise in various BSM theories
  - Left-right symmetric models, little Higgs model, type-II seesaw models, ...

- Appear in  $SU(2)_L$  triplet for almost all the models studied

$$\Delta = \begin{pmatrix} H^+/\sqrt{2} & H^{++} \\ H^0 = \frac{1}{\sqrt{2}}(\delta + v_\Delta + i\eta) & -H^+/\sqrt{2} \end{pmatrix}$$

- The Yukawa interaction term

$$-Y_\nu \bar{l}_L^c i\sigma_2 \Delta l_L + h.c.$$

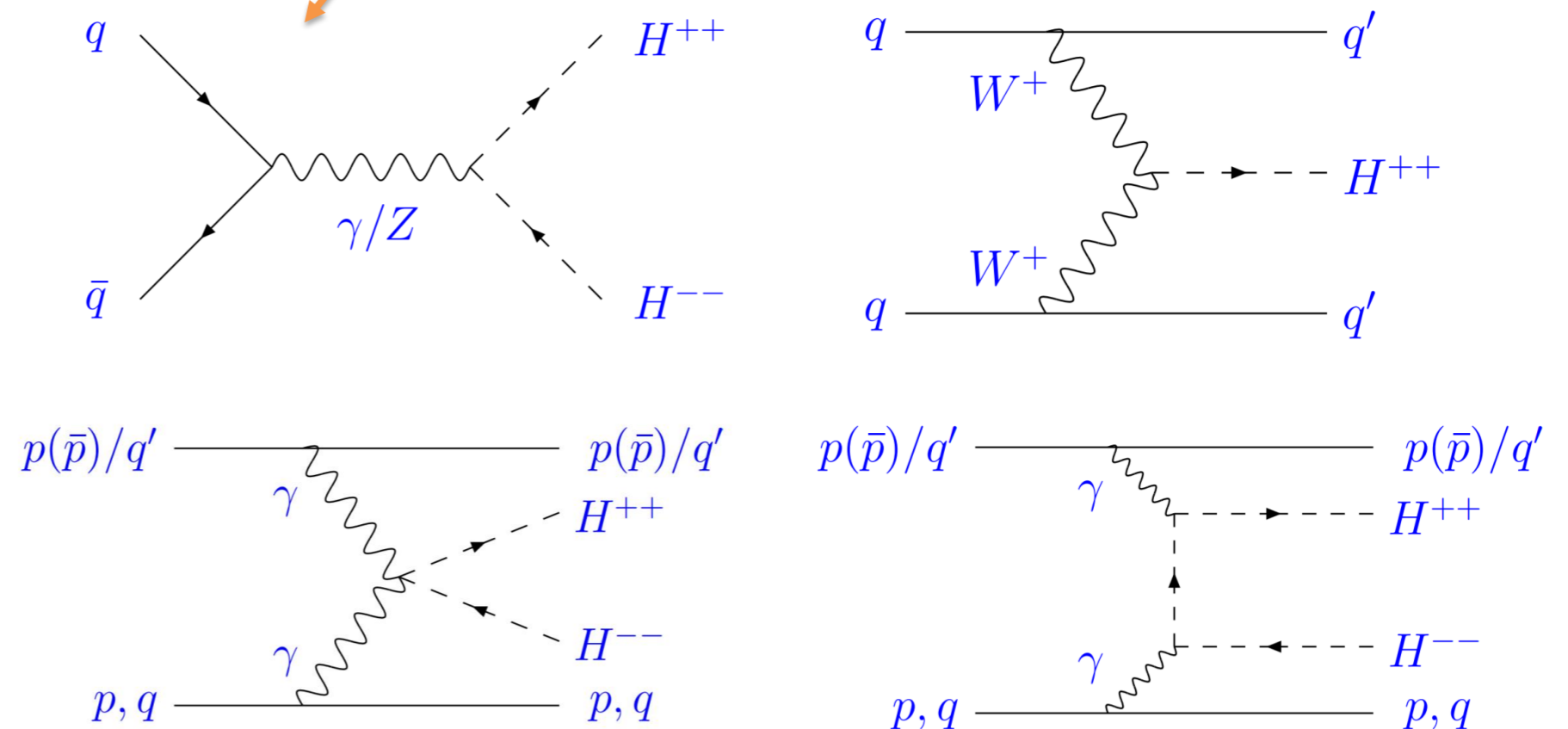
and the neutrinos acquire a Majorana mass

$$M_\nu = \sqrt{2} Y_\nu v_\Delta \approx Y_\nu \frac{\mu v_0^2}{M_\Delta^2}$$

- Can decay to a pair of same-sign leptons which are rare in SM

- Signal violation of lepton flavour by two units

Dominant Drell-Yan pair production



Feynman diagrams for several doubly charged Higgs production channel. arXiv:1105.1379v1

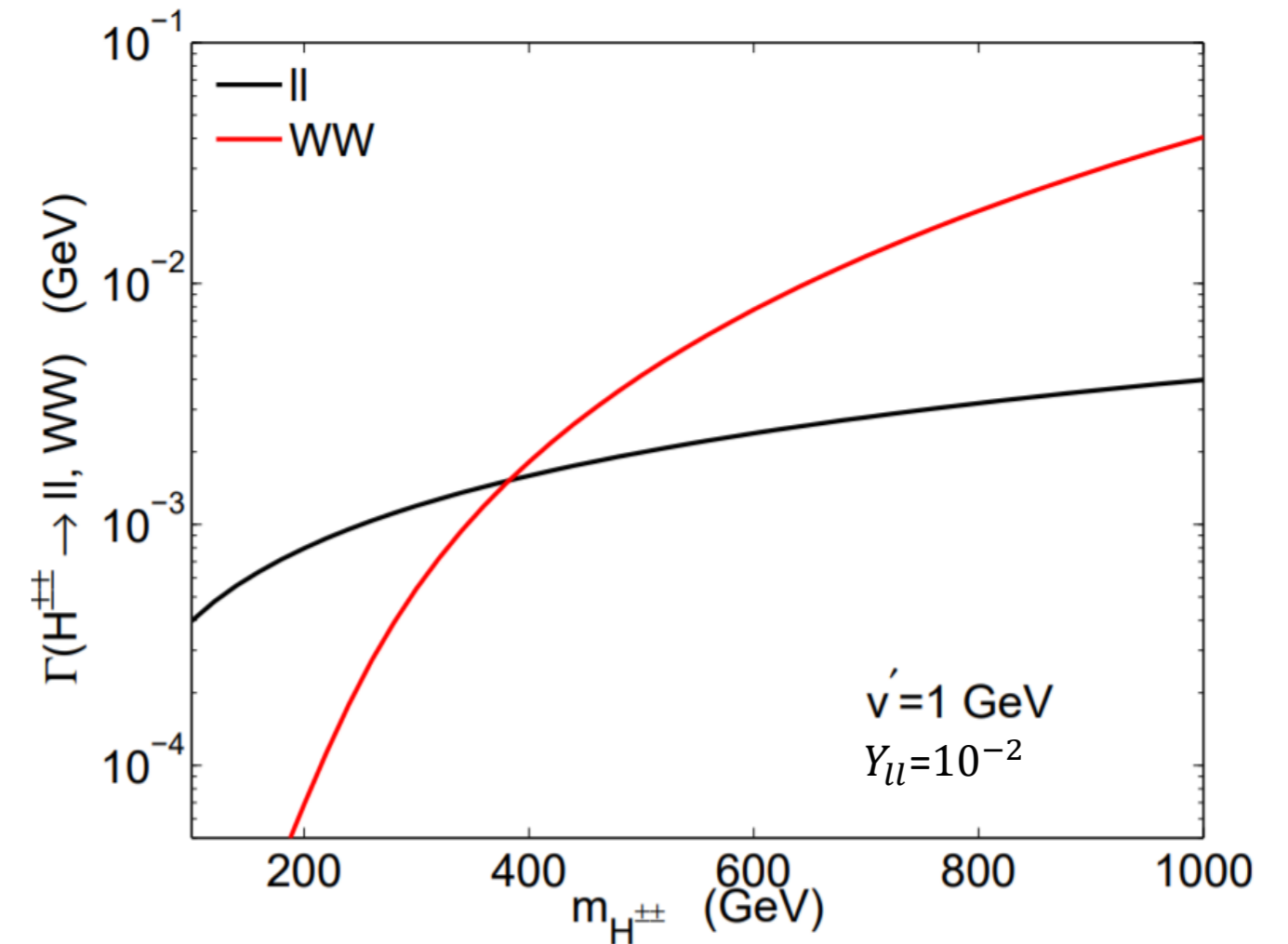


# Previous study by ATLAS on $H^{\pm\pm} \rightarrow l^{\pm}l'^{\pm}$

- Used pp data sample with Integrated luminosity 36.1  $fb^{-1}$  collected in 2015 and 2016 by the ATLAS detector at the LHC at  $\sqrt{s}=13$  TeV
- Only pair production via the Drell–Yan process was considered
- Total assumed branching ratio of  $H^{\pm\pm}$  is  $B(H^{\pm\pm} \rightarrow l^{\pm}l'^{\pm}) + B(H^{\pm\pm} \rightarrow X) = 100\%$ , while “X” does not enter any of the SRs. Only  $e$  and  $\mu$  were considered.
- Partial decay width of  $H^{\pm\pm}$  to leptons is given by:

$$\Gamma(H^{\pm\pm} \rightarrow l^{\pm}l'^{\pm}) = \frac{1}{1 + \delta_{ll'}} \frac{|\tilde{Y}_{ll'}|^2 m_{H^{\pm\pm}}}{16\pi}, \quad \tilde{Y}_{ll'} = \begin{cases} 2Y_{ll'} & l = l' \\ Y_{ll'} & l \neq l' \end{cases}$$

- Masses studied:  $200 \leq m_{H^{\pm\pm}} \leq 1300$  GeV  $|\tilde{Y}_{ll'}|^2 = 2|m_{\nu}^{ij}|^2/v_{\Delta}^2$



Branching ratios of  $H^{\pm\pm}$  into different final states vs. mass of  $H^{\pm\pm}$  for  $v_{\Delta} = 1$  GeV,  $Y_{ll} = 0.01$ . arXiv:1105.1379v1



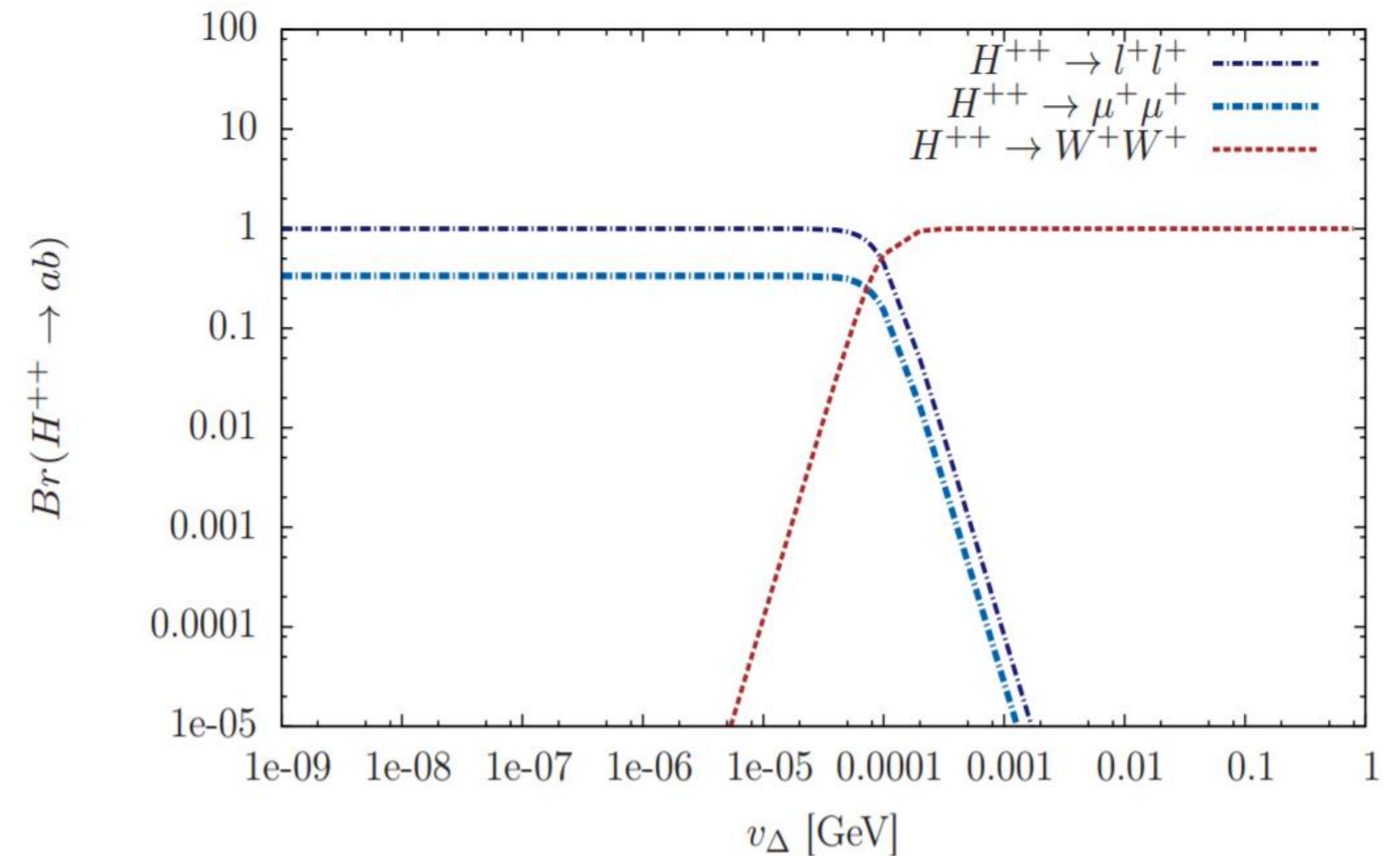
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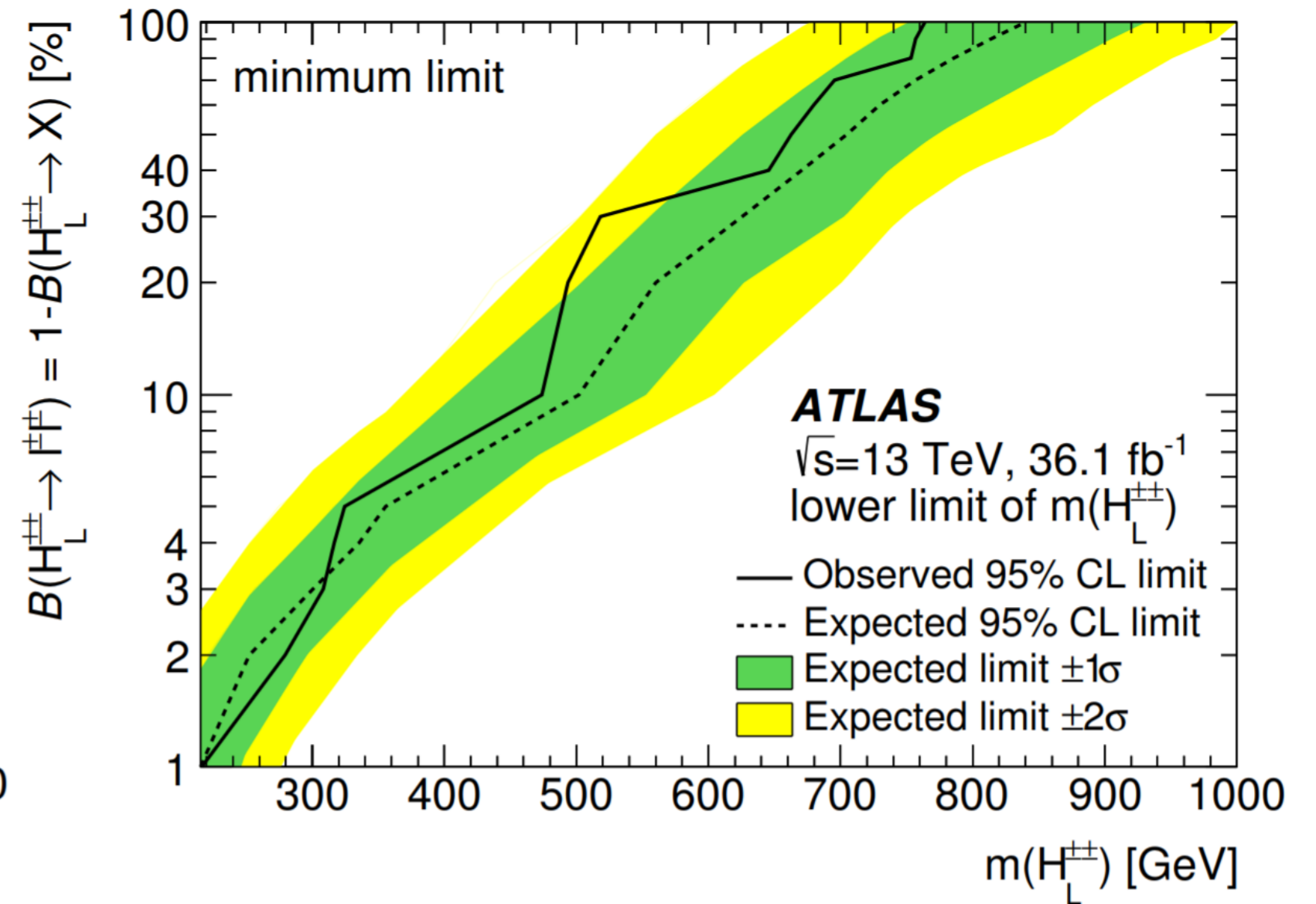
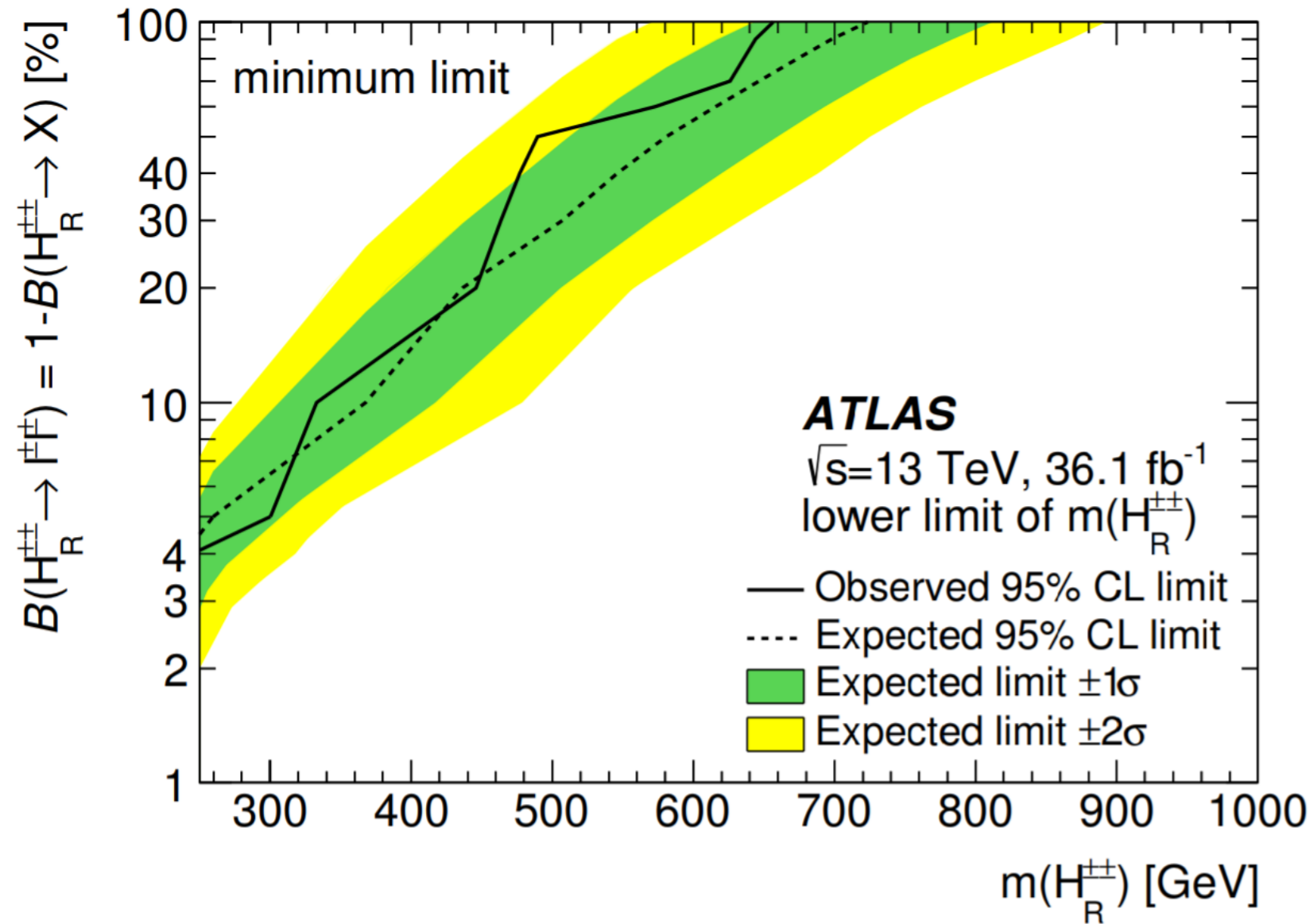
$$|\tilde{Y}_{ll'}|^2 = 2|m_v^{ij}|^2/v_{\Delta}^2$$



Branching ratios of  $H^{\pm\pm}$  into different final states vs. vacuum expectation value. arXiv:1611.09594v2



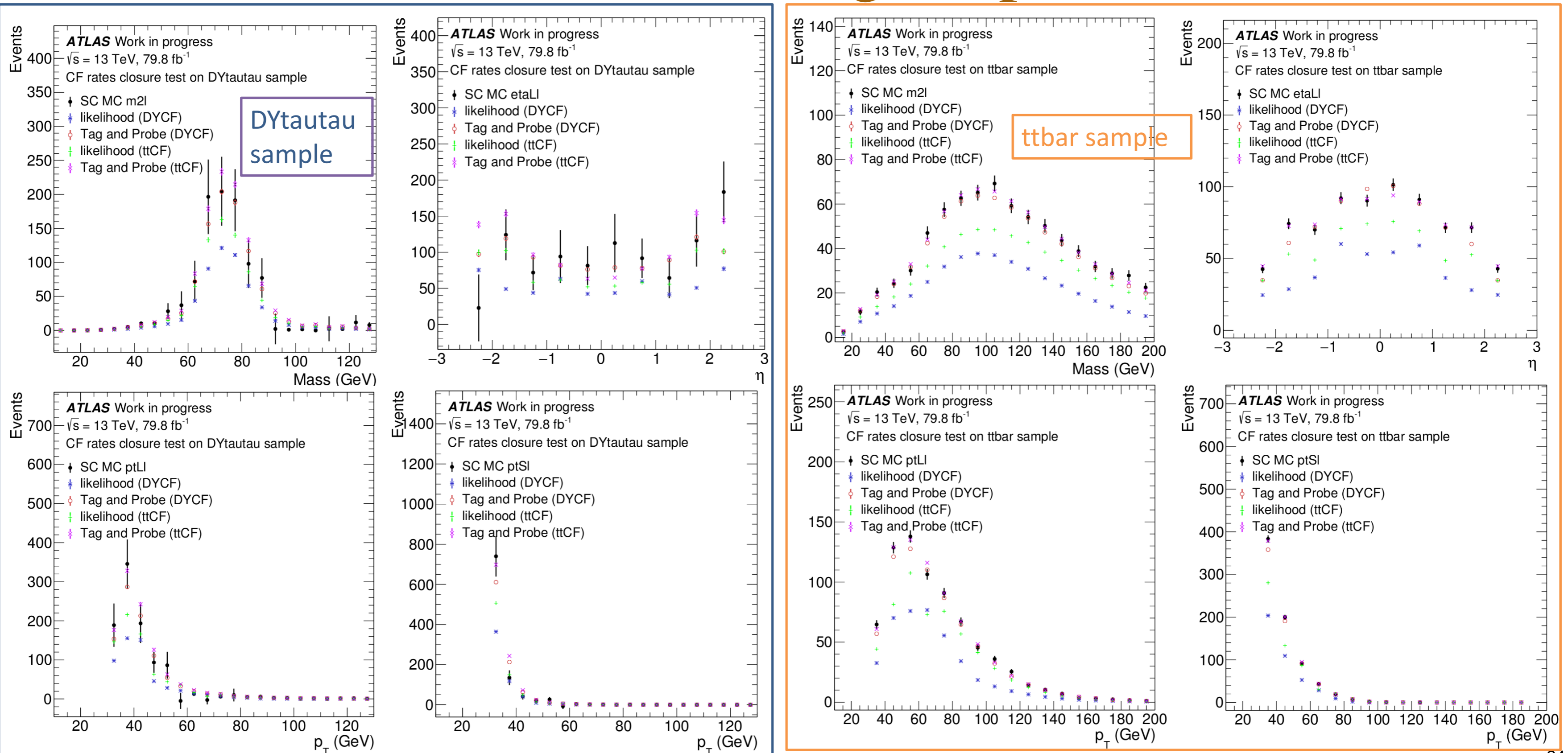
# Lower-limit plots on $H_L^{\pm\pm}$ and $H_R^{\pm\pm}$ mass



arXiv: 1710.09748v1

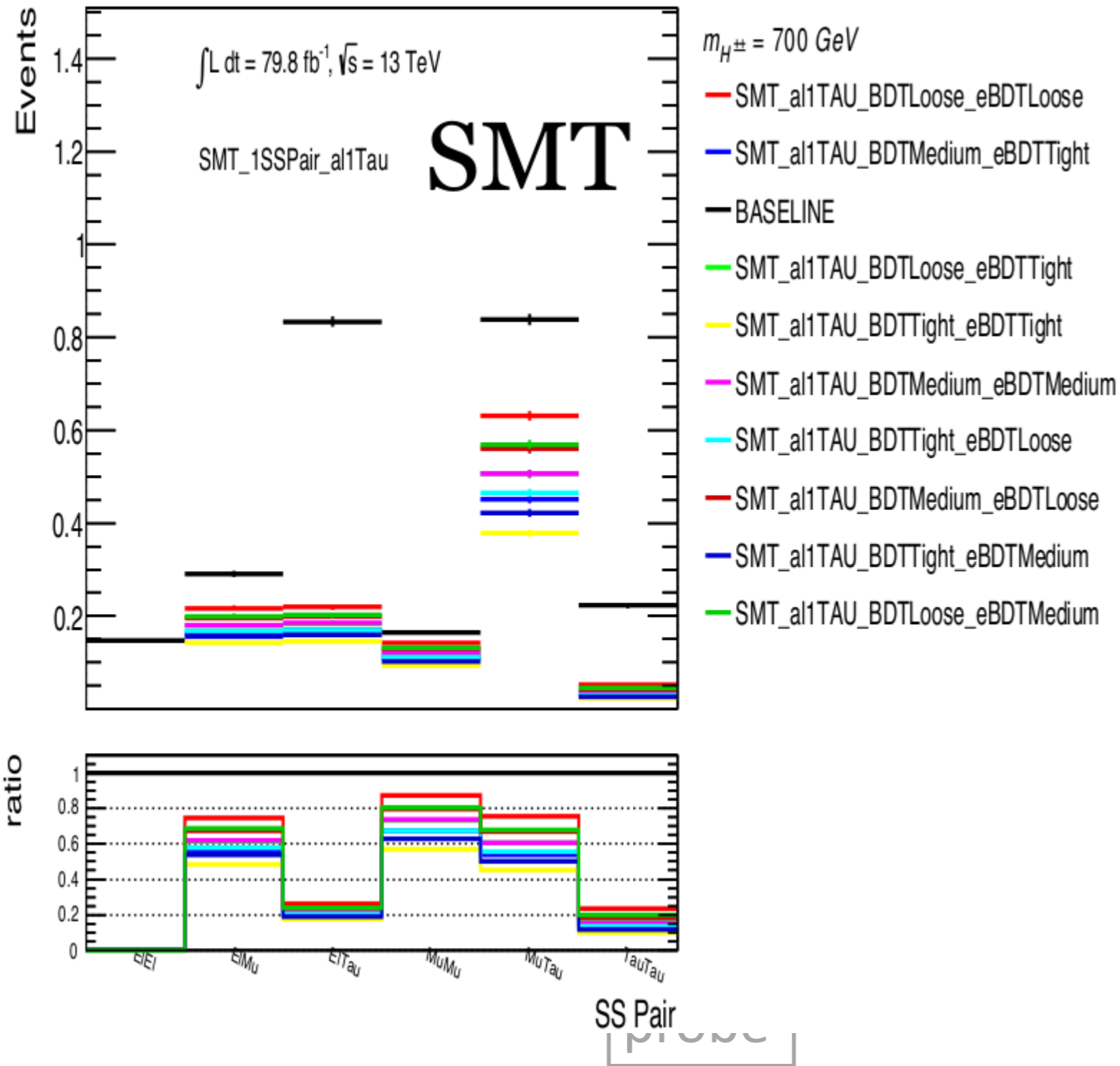


# Closure test for the MC charge flip rate



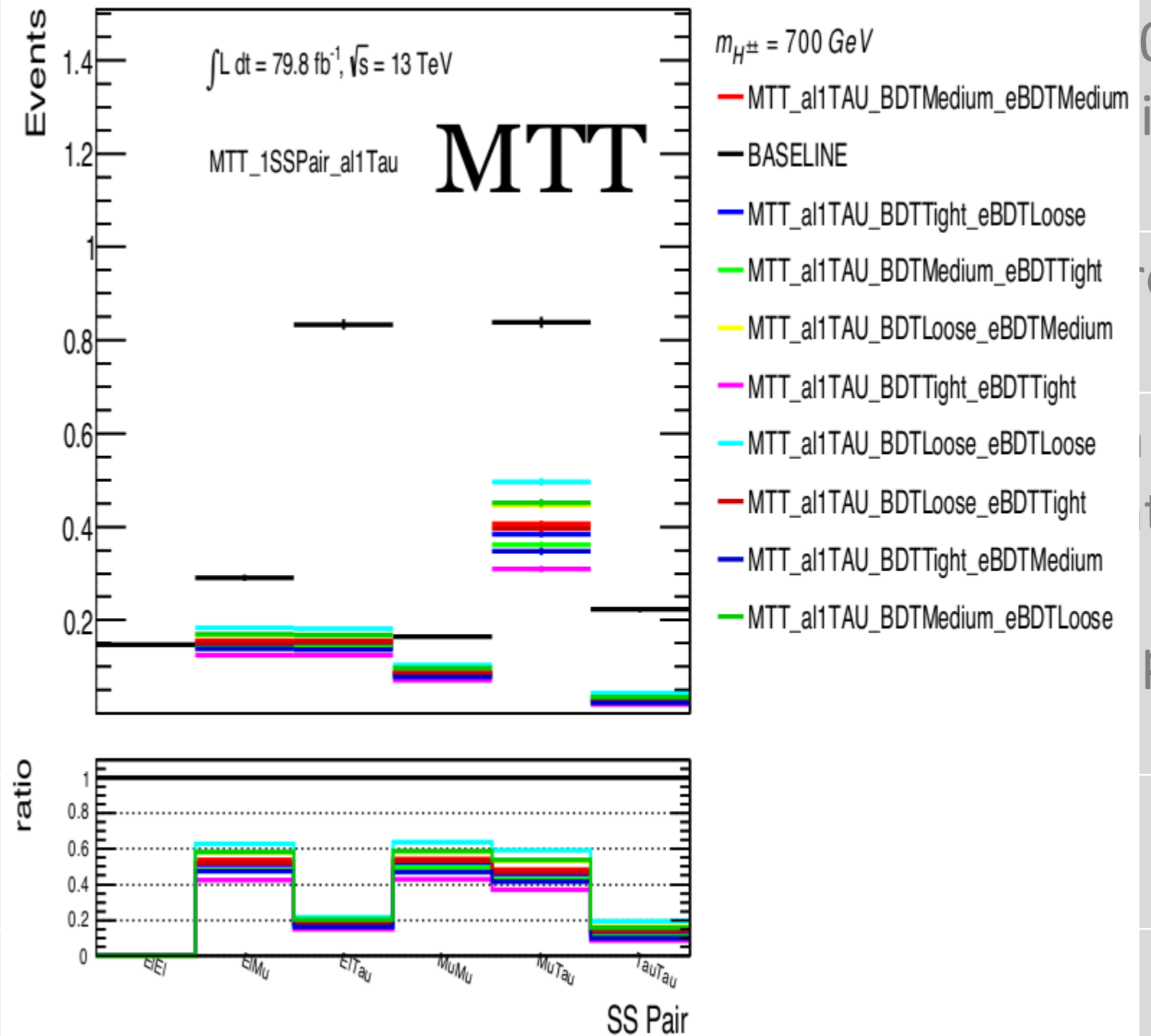


# Tag-and-probe method



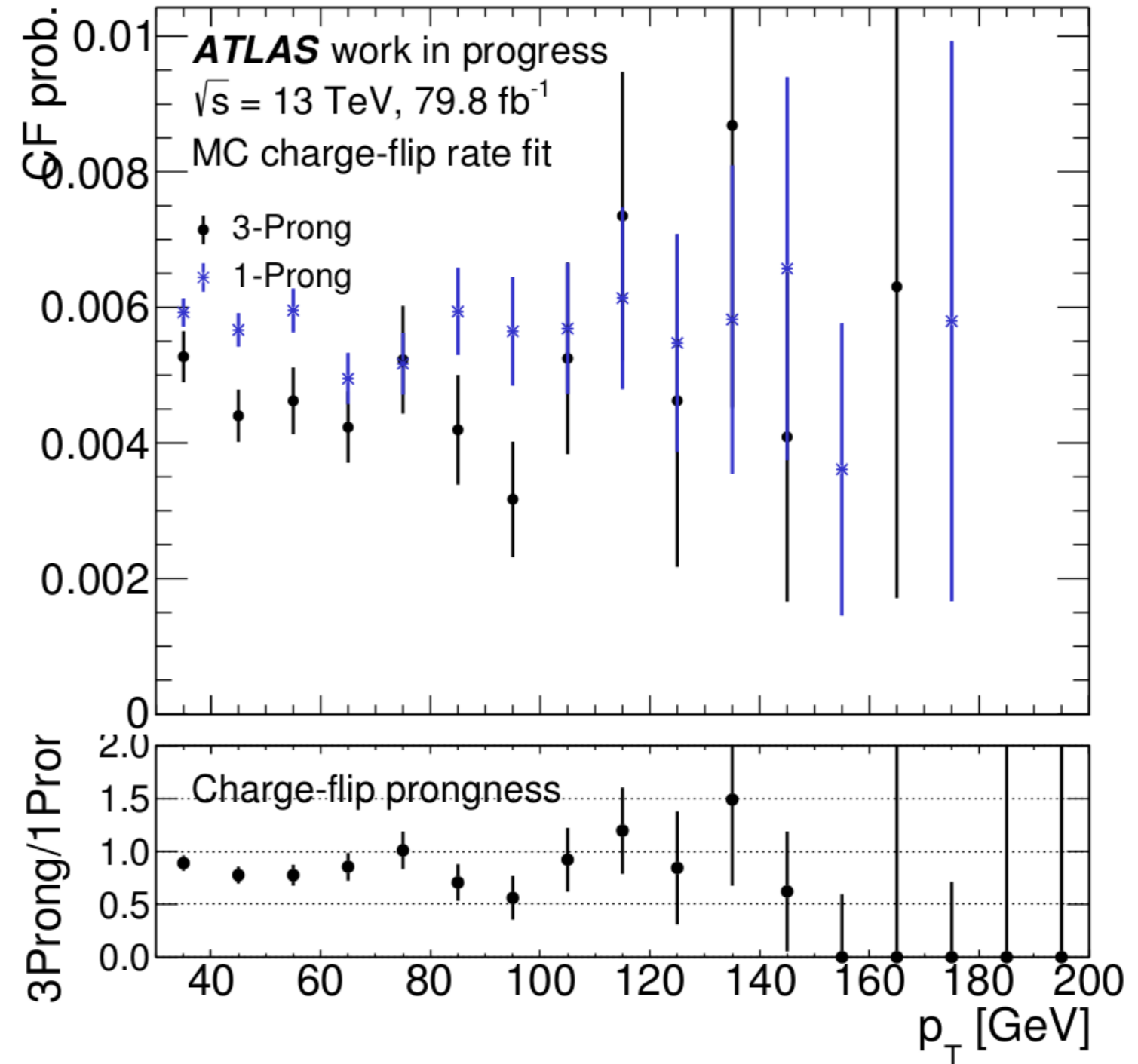
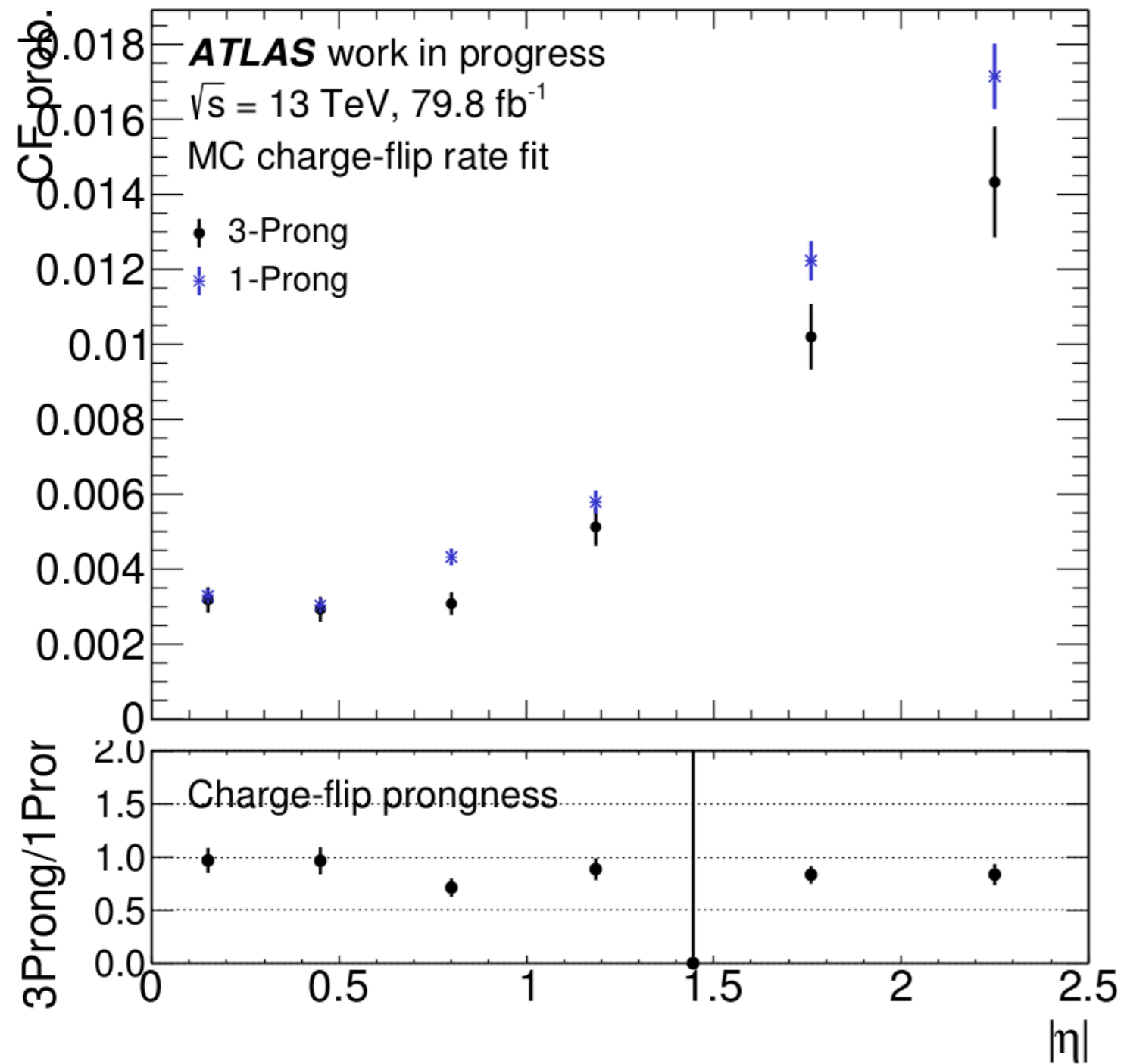
## Selections

Single muon trigger:



0  
ium  
on  
wp,  
theta  
p,

# 1D charge-flip rate with prongness from $t\bar{t}$



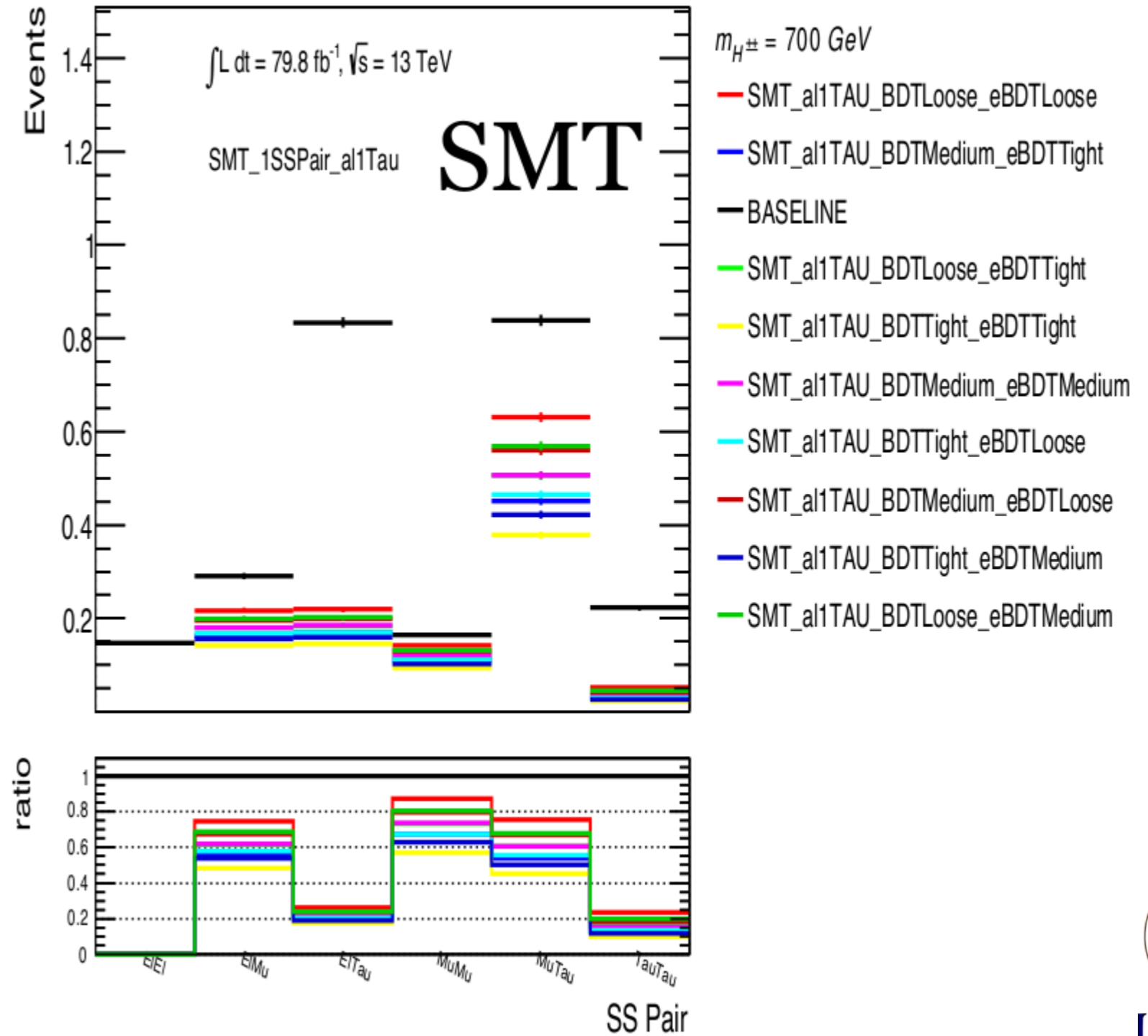
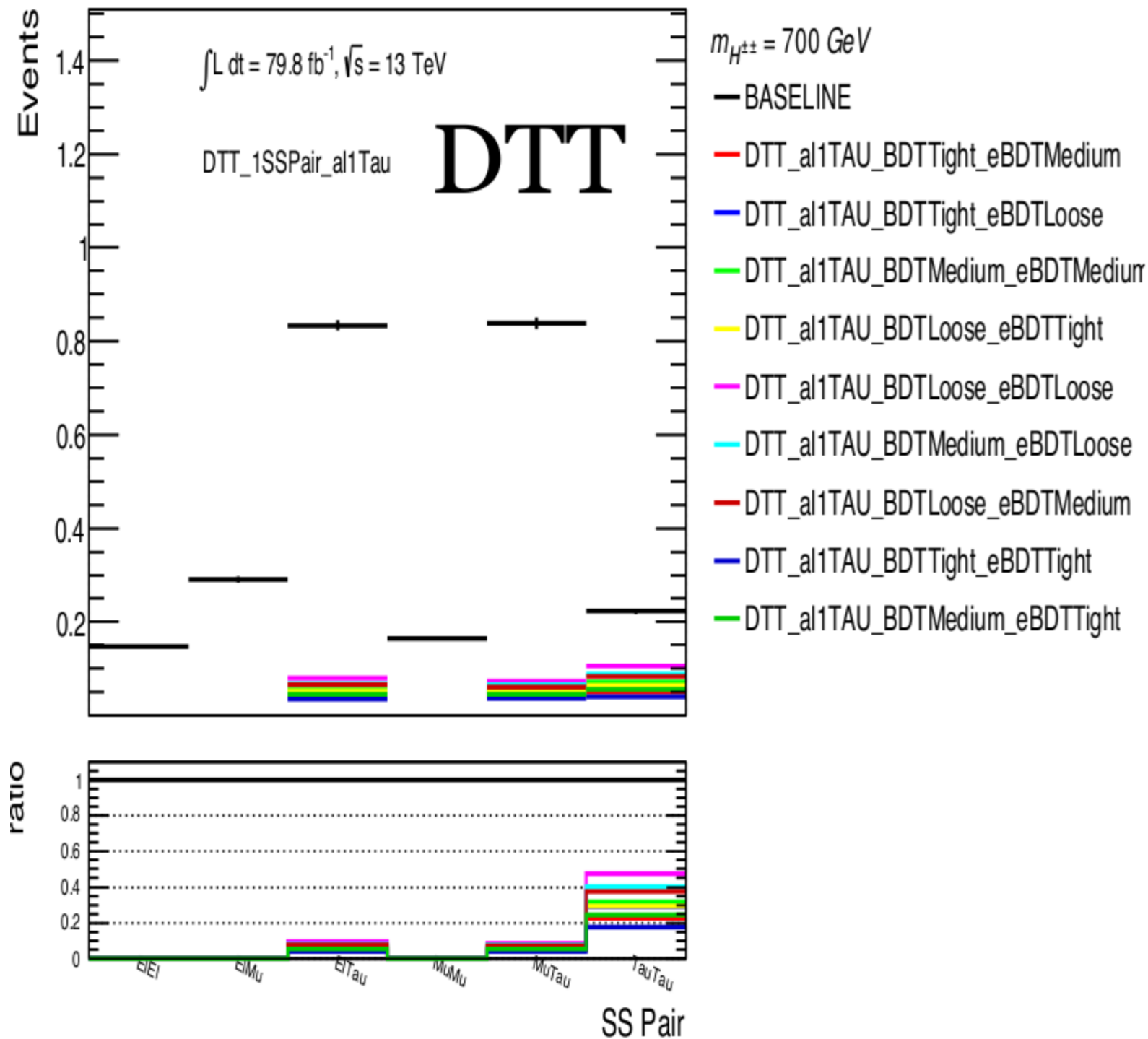
# Tau Charge-flip rate for data

- Use recommended selections for Z and ttbar control regions

	Selections
Baseline	Single muon trigger
	One muon and one tau. Electron veto
	Muon: $p_T > 30$ GeV, medium wp, FixedCutTightTrackOnly, $z0\sin\theta < 0.5$ , $d0\text{sig} < 3.0$ Tau: $p_T > 30$ GeV, medium wp, isoTau, hadronic tau
Z control region	$m_T(\mu, E_T^{\text{miss}}) = \sqrt{2p_T(\mu)E_T^{\text{miss}}(1 - \cos \Delta\Phi(\mu, E_T^{\text{miss}}))} < 50$ GeV
	$\cos \Delta\Phi(\mu, E_T^{\text{miss}}) + \cos \Delta\Phi(\tau, E_T^{\text{miss}}) > 0.5$
ttbar control region	Tau: $p_T > 50$ GeV, muon: $p_T > 50$ GeV
	At least one b-jet

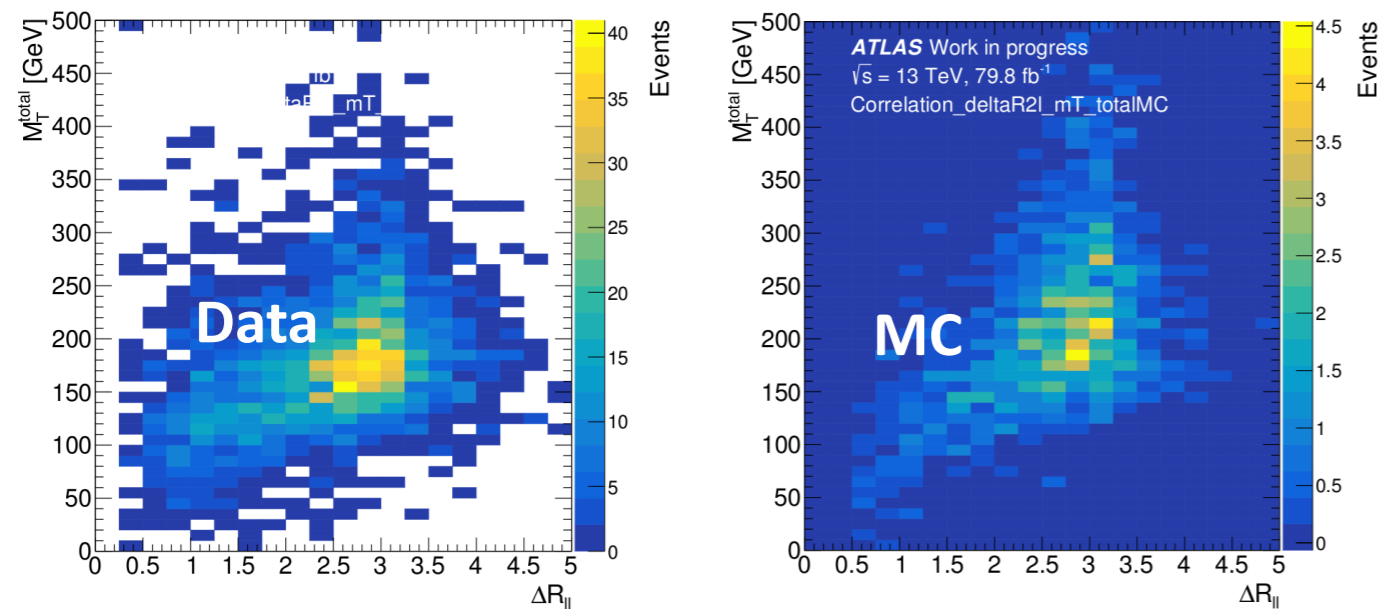
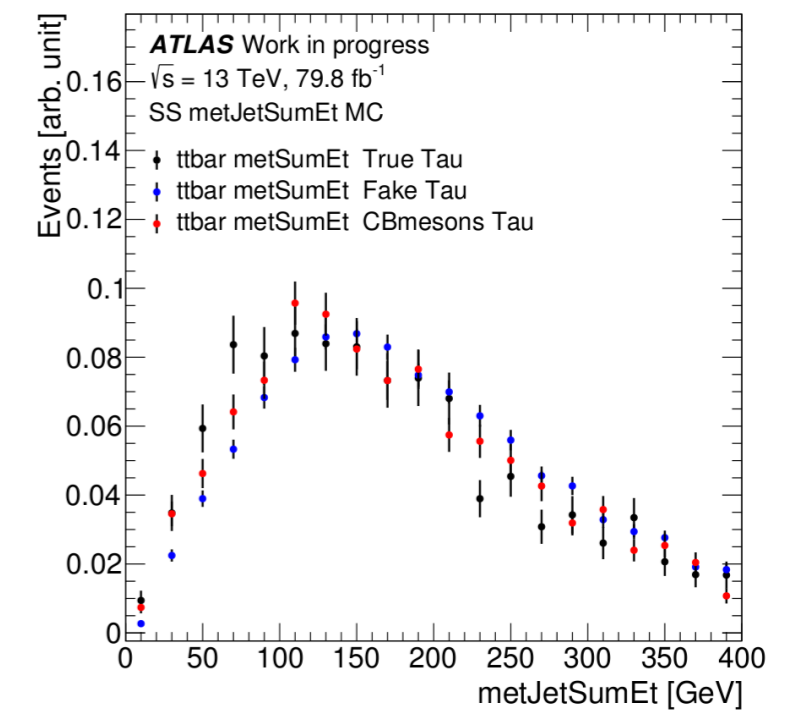
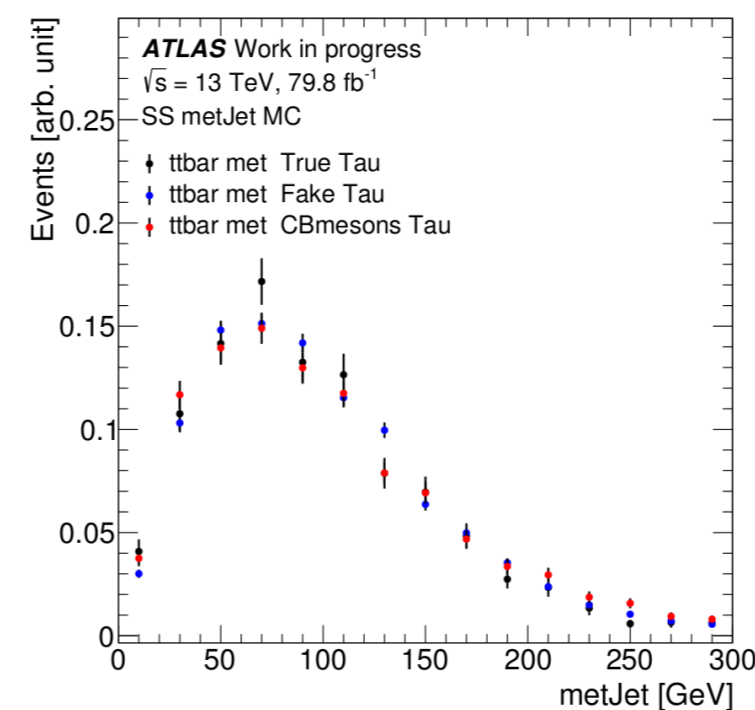
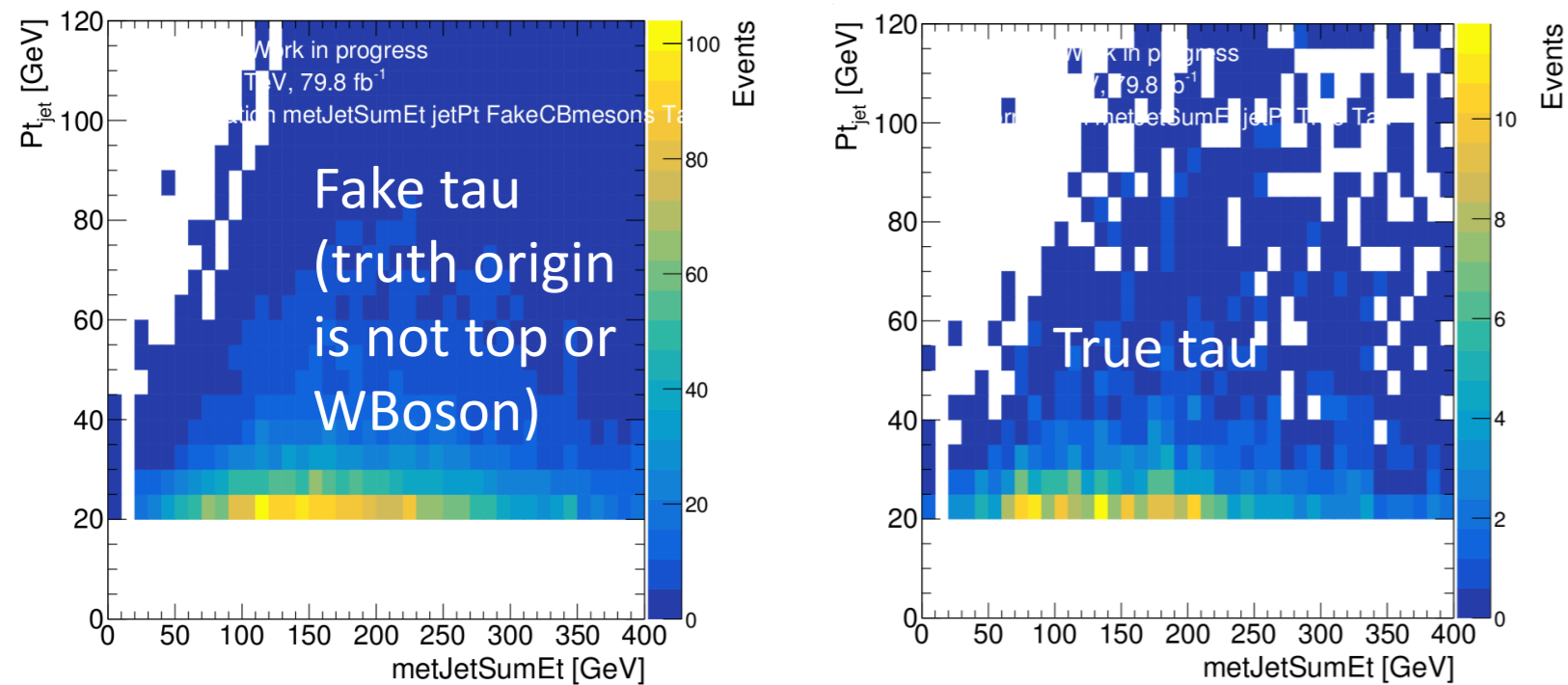


# Why choose mu tau channel for template fit



# Attempts to reduce the background

- A lot of efforts were spent on studying the correlations and distributions of tau and jet kinematic variables, but it seems that the BDT has already done a good job with selecting events with same topology



No significant difference. It is not easy to reduce fake tau SS background.

# Template fit method

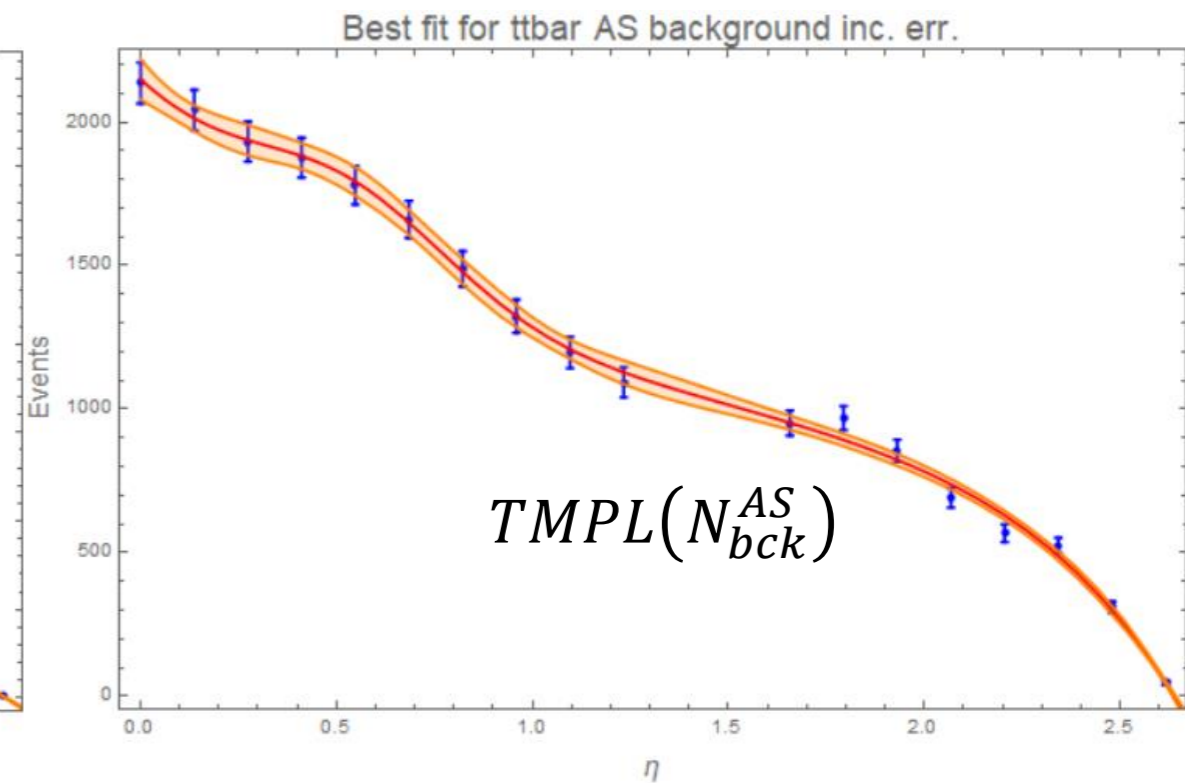
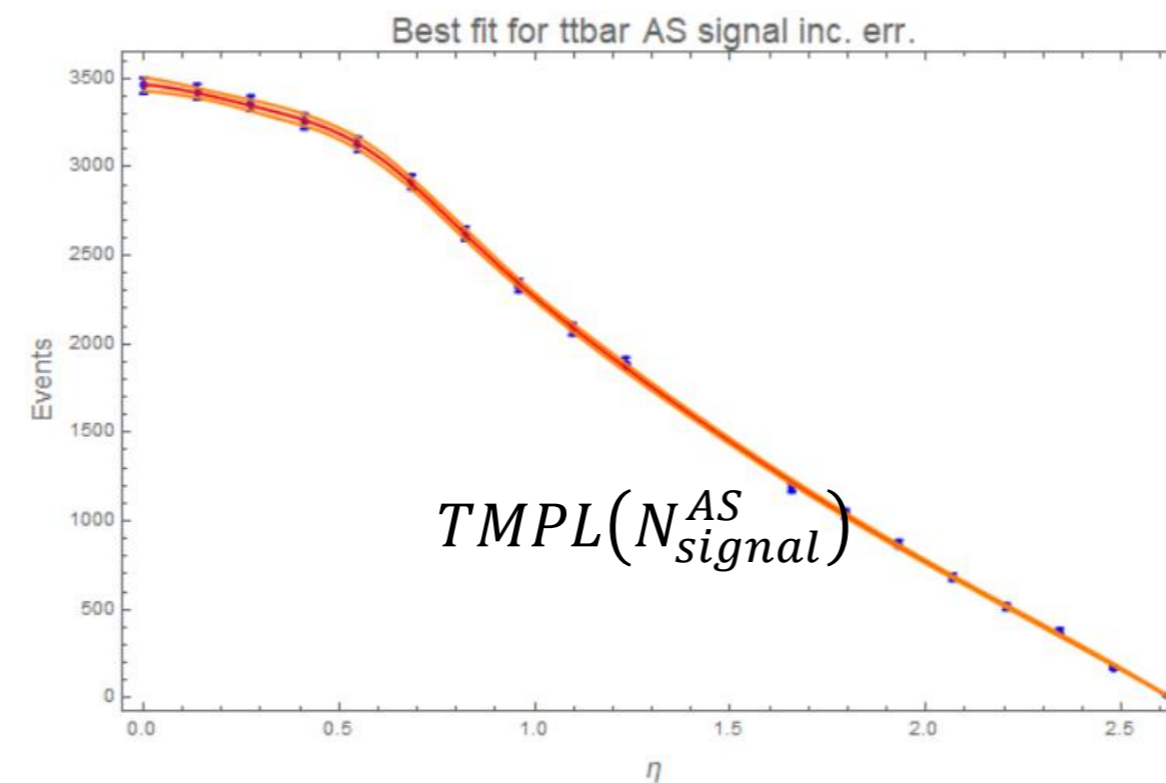
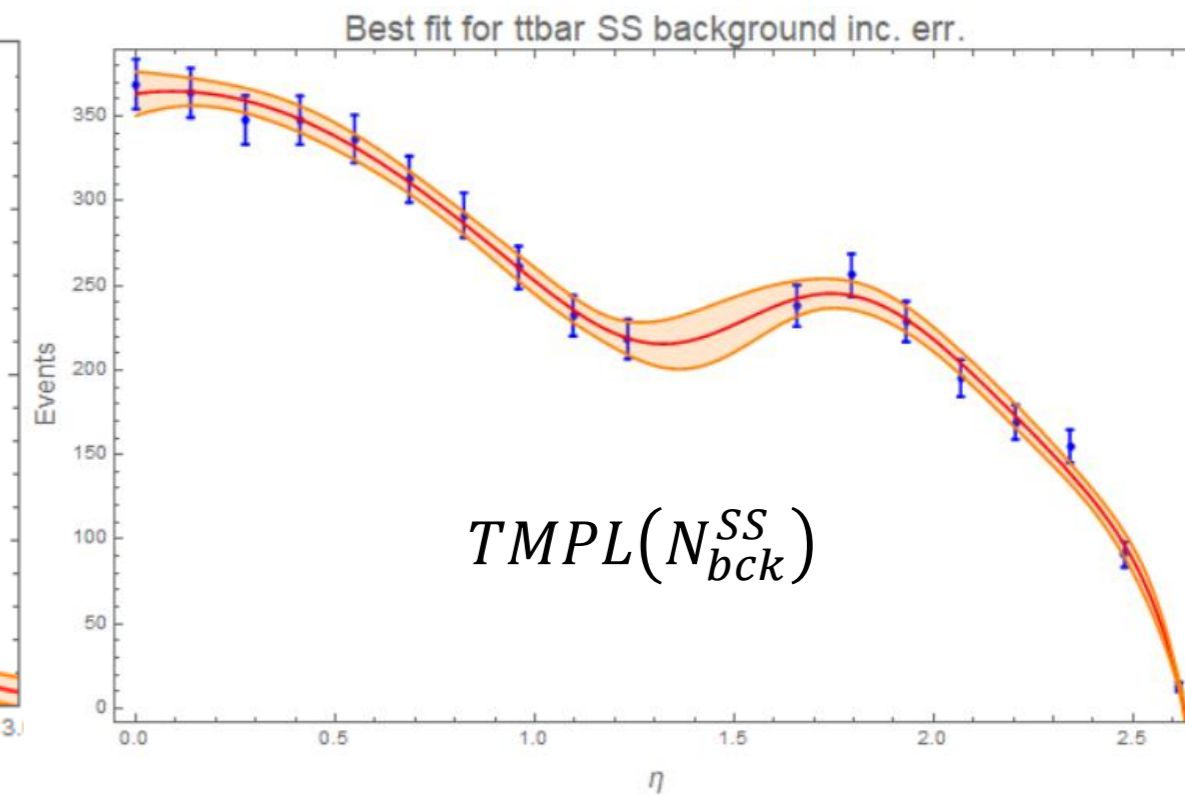
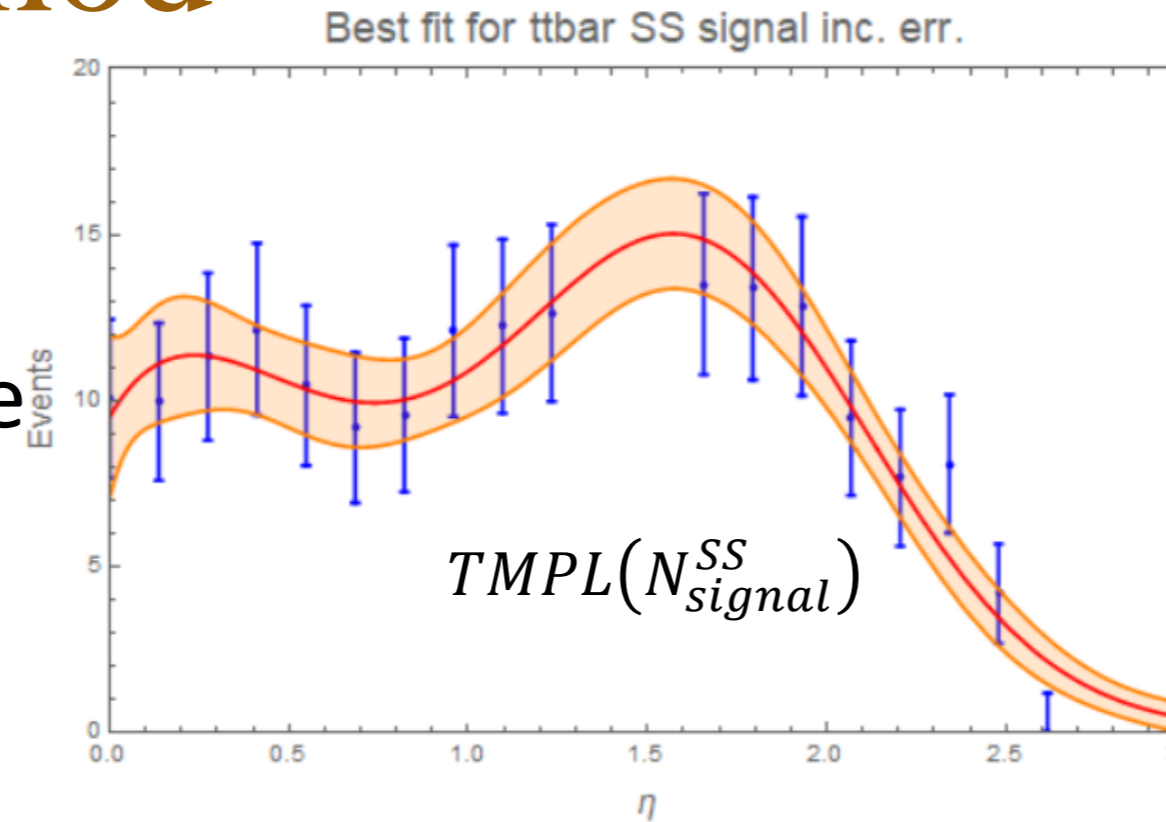
- Perform fitting in Mathematica 11.1
- The models generally have the form:

$$\frac{(ax + b)}{ef(x)}$$

or

$$\frac{(ax + b)}{ef(x)} + \text{Gaussian}(x)$$

where  $f(x)$  is a polynomial of  $x$

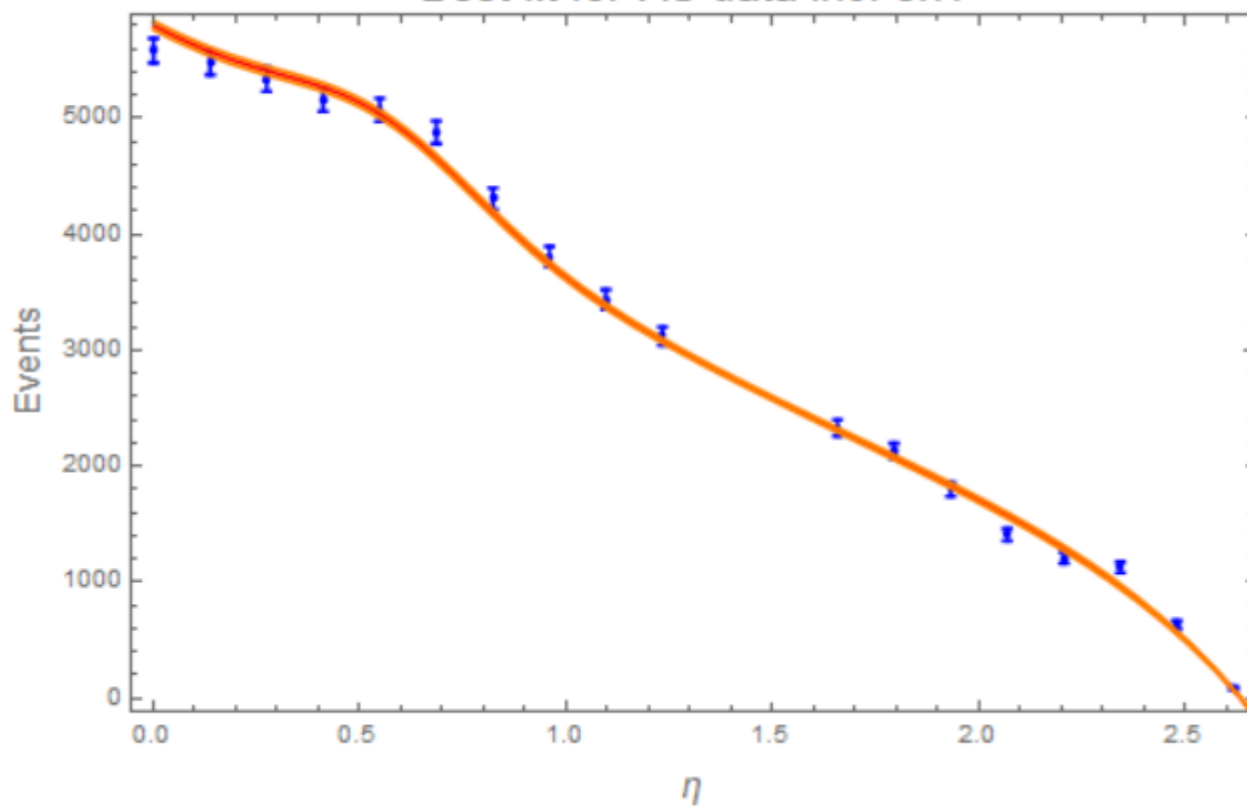


# Template fit method

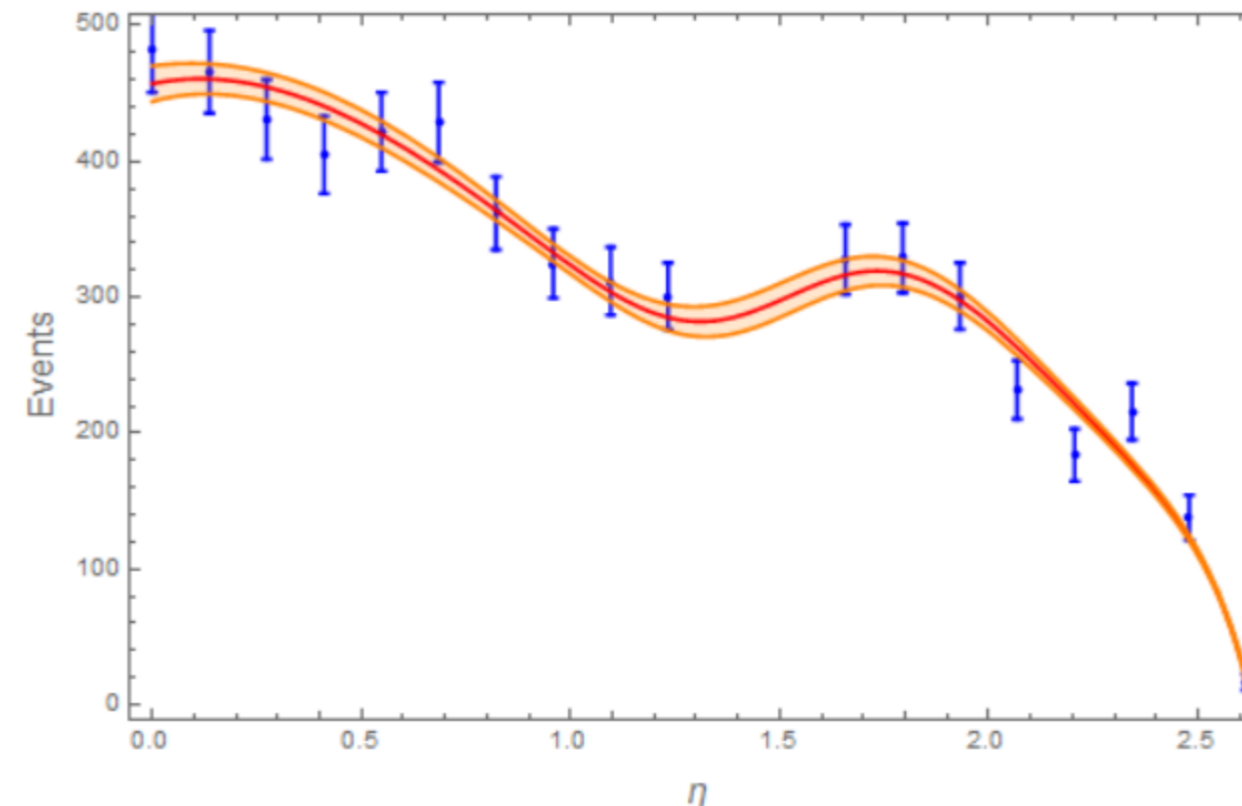
- Need to find optimum values for the parameter  $a, b, c, d$ :

$$N_{data}^{AS}(\eta_i) = a \cdot TMPL \left( N_{signal}^{AS}(\eta_i) \right) + b \cdot TMPL \left( N_{bck}^{AS}(\eta_i) \right)$$
$$N_{data}^{SS}(\eta_i) = c \cdot TMPL \left( N_{signal}^{SS}(\eta_i) \right) + d \cdot TMPL \left( N_{bck}^{SS}(\eta_i) \right)$$

Best fit for AS data inc. err.



Best fit for SS data inc. err.



# Our group

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<https://twiki.cern.ch/twiki/bin/viewauth/AtlasProtected/SameSignClusterRun2>

